
Peripherals of Freescale Kinetis microcontrollers

Part 2

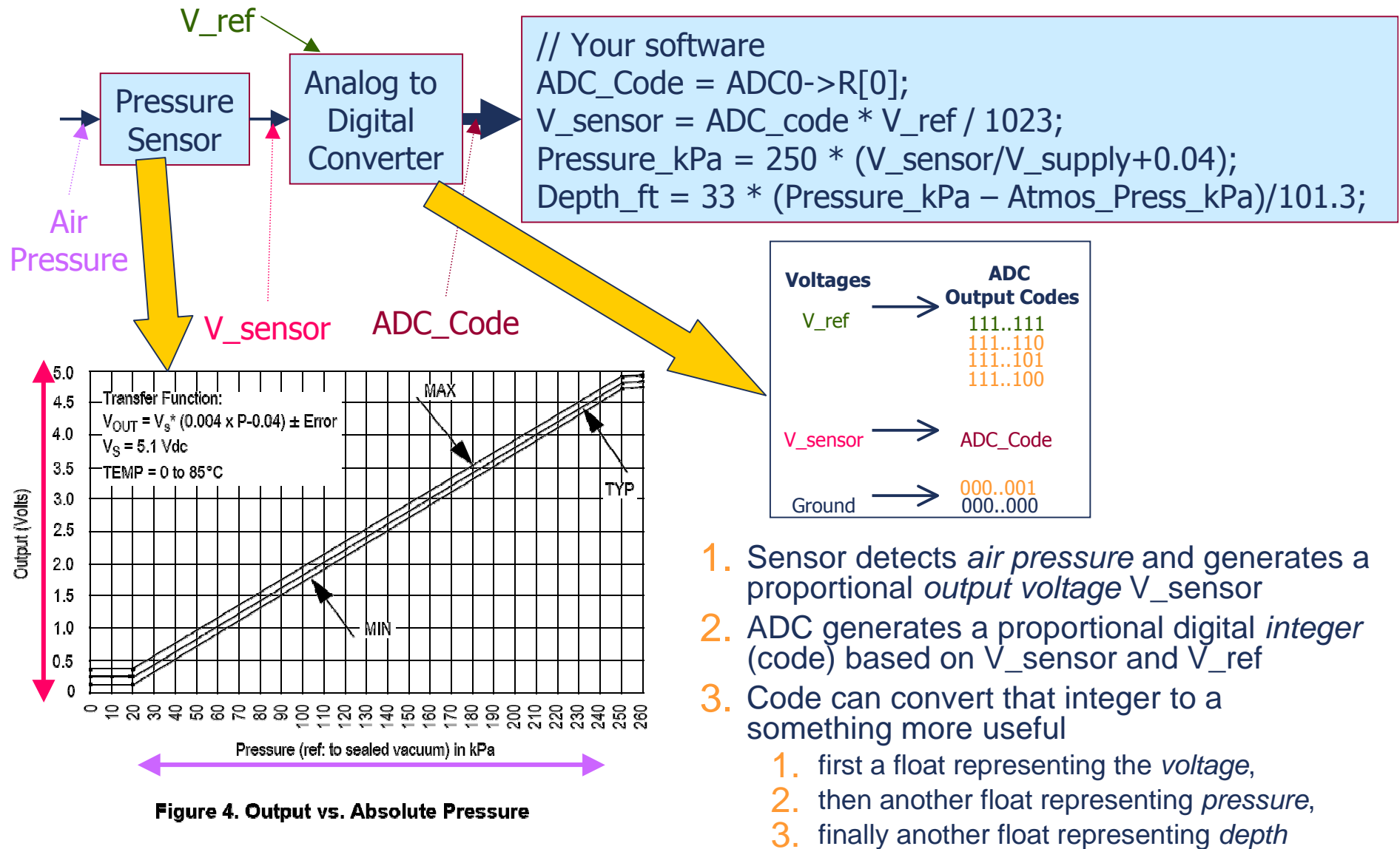
Analog Interfacing

Outline

- **Basics of analog to digital conversion**
- **KinetisL25 analog peripherals**
 - Digital to Analog Converter (DAC)
 - Comparator
 - Analog to Digital Converter (ADC)

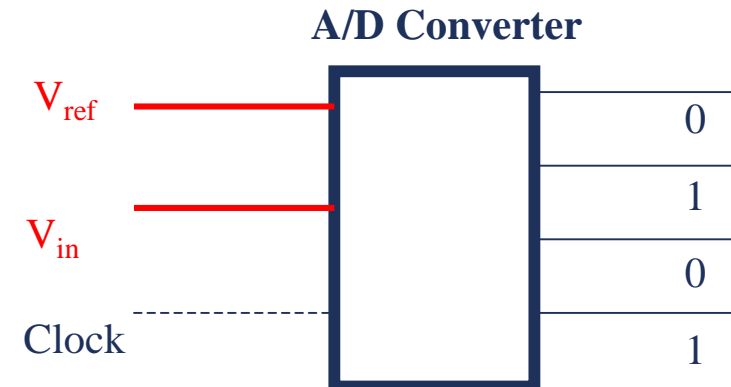
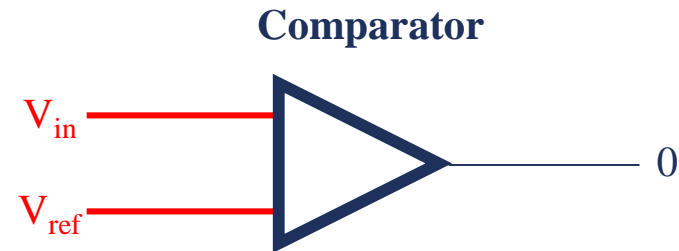
CONVERTING BETWEEN ANALOG AND DIGITAL VALUES

The Big Picture – A Depth Gauge



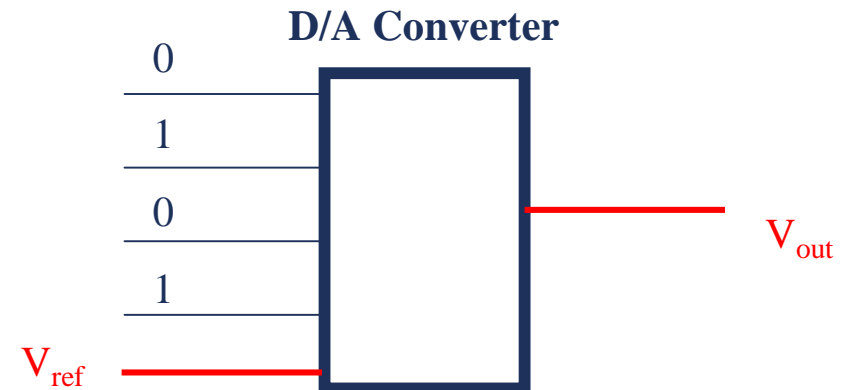
Getting From Analog to Digital

- **A Comparator tells us “Is $V_{in} > V_{ref}$?”**
 - Compares an **analog input voltage** with an **analog reference voltage** and determines which is larger, returning a 1-bit number
 - E.g. Indicate if depth > 100 ft
 - Set V_{ref} to voltage pressure sensor returns with 100 ft depth.
- **An Analog to Digital converter [AD or ADC] tells us how large V_{in} is as a fraction of V_{ref} .**
 - Reads an analog input signal (usually a voltage) and produces a corresponding multi-bit number at the output.
 - E.g. calculate the depth

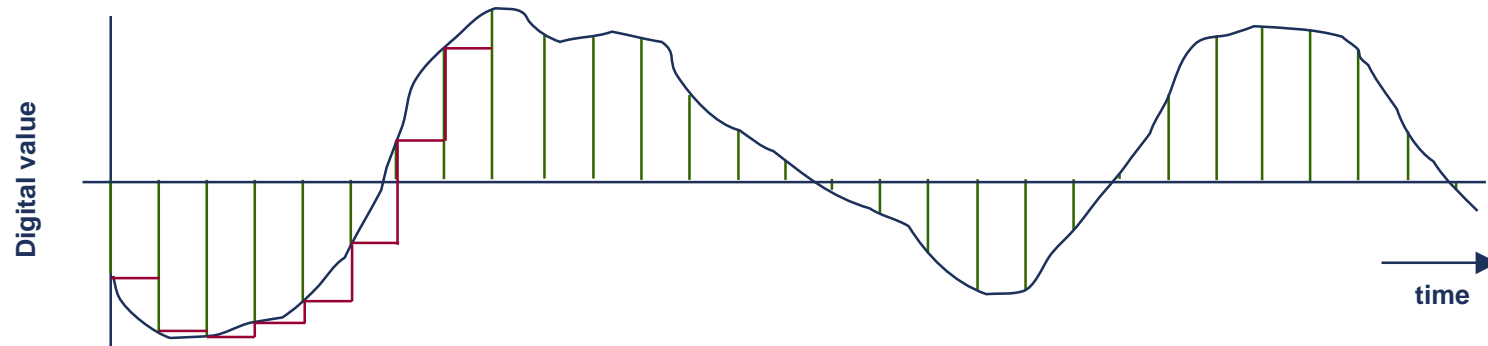


Digital to Analog Conversion

- May need to generate an analog voltage or current as an output signal
 - E.g. audio signal, video signal brightness.
- DAC: “Generate the analog voltage which is this fraction of V_{ref} ”
- Digital to Analog Converter equation
 - n = input code
 - N = number of bits of resolution of converter
 - V_{ref} = reference voltage
 - V_{out} = output voltage. Either:
 - $V_{out} = V_{ref} * n/(2^N)$ or
 - $V_{out} = V_{ref} * (n+1)/(2^N)$
 - *The offset +1 term depends on the internal tap configuration of the DAC – check the datasheet to be sure*



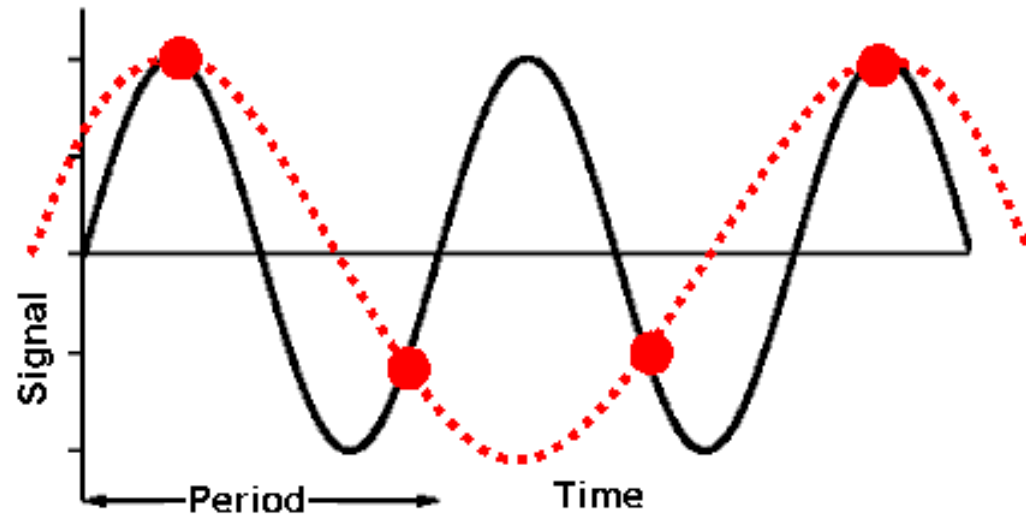
Waveform Sampling and Quantization



- A waveform is sampled at a constant rate – every Δt
 - Sampling converts a **continuous time** signal to a **discrete time** signal
- The sample can now be quantized (converted) into a digital value
 - Quantization represents a **continuous** (analog) value with the closest **discrete** (digital) value

Sampling problem example

- Consider if we sample a signal at 1.5 times it's period.
- In the graph below the black line shows the actual signal fluctuation, while the red dots show our samples.
- Observing our samples, we would infer that the signal was half it's actual frequency (dotted red line)

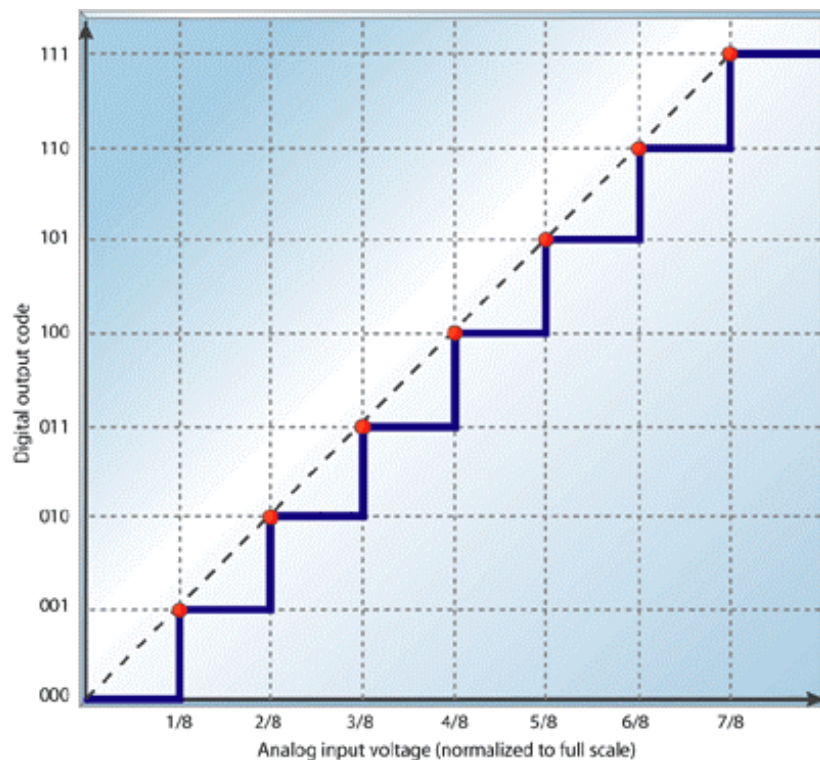


Nyquist criterion

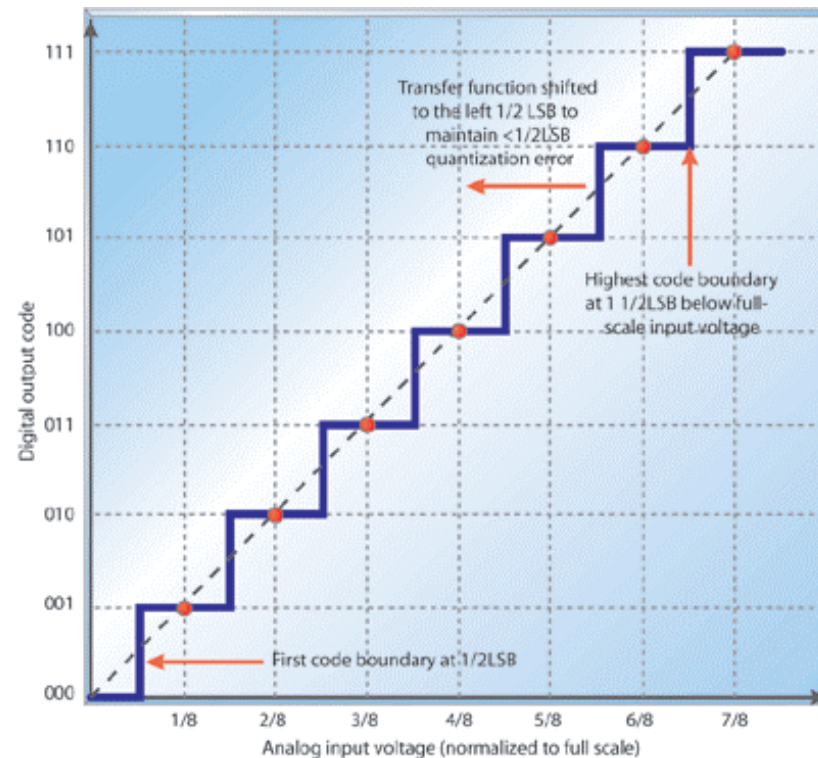
- $F_{\text{sample}} \geq 2 * F_{\text{max frequency component}}$
- Frequency components above $\frac{1}{2} F_{\text{sample}}$ are **aliased**, distort measured signal
- **Nyquist and the real world**
 - This theorem assumes we have a perfect analog filter with “brick wall” roll-off
 - Real world filters have more gentle roll-off
 - Inexpensive filters are even worse (e.g. first order filter is 20 dB/decade, aka 6 dB/octave)
 - **So we have to choose a sampling frequency high enough that our filter attenuates aliasing components adequately**

Analog to Digital Transfer functions

- Ideal transfer function for a 3-bit ADC with reference points at code transition boundaries.
- Maximum quantization error is 1 LSB (Least Significant Bit) i.e. $1/8 V_{\text{ref}}$ for 3-bit ADC



- The transfer function implemented with an offset of $-1/2$ LSB
- This shift of the transfer function to the left shifts the quantization error from a range of $(-1 \text{ to } 0 \text{ LSB})$ to $(-1/2 \text{ to } +1/2 \text{ LSB})$.



Forward Transfer Function Equations

What code n will the ADC use to represent voltage V_{in} ?

n = converted code

V_{in} = sampled input voltage

V_{ref} = voltage reference

N = number of bits of resolution in ADC

$$n = \left\lfloor 2^N * \frac{V_{in}}{V_{ref}} + \frac{1}{2} \right\rfloor$$

$\lfloor X \rfloor = I$ *floor function: nearest integer I such that $I \leq X$*
floor $(x+0.5)$ rounds x to the nearest integer

Inverse Transfer Function

What range of voltages V_{in_min} to V_{in_max} does code n represent?

$$V_{in_min} = \frac{n - \frac{1}{2}}{2^N} V_{ref}$$

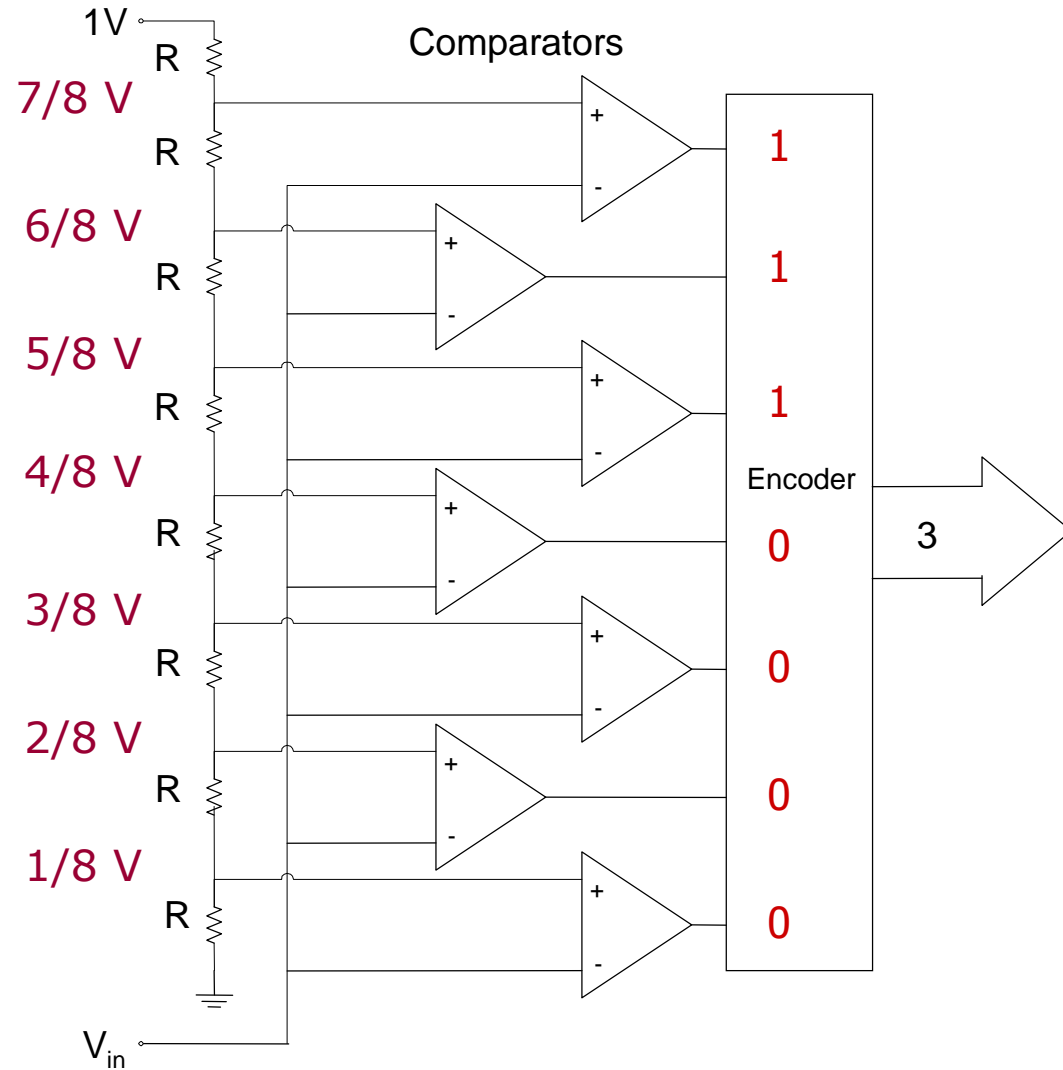
$$V_{in_max} = \frac{n + \frac{1}{2}}{2^N} V_{ref}$$

$$V_{in_avg} = \frac{n}{2^N} V_{ref}$$

ANALOG TO DIGITAL CONVERSION CONCEPTS

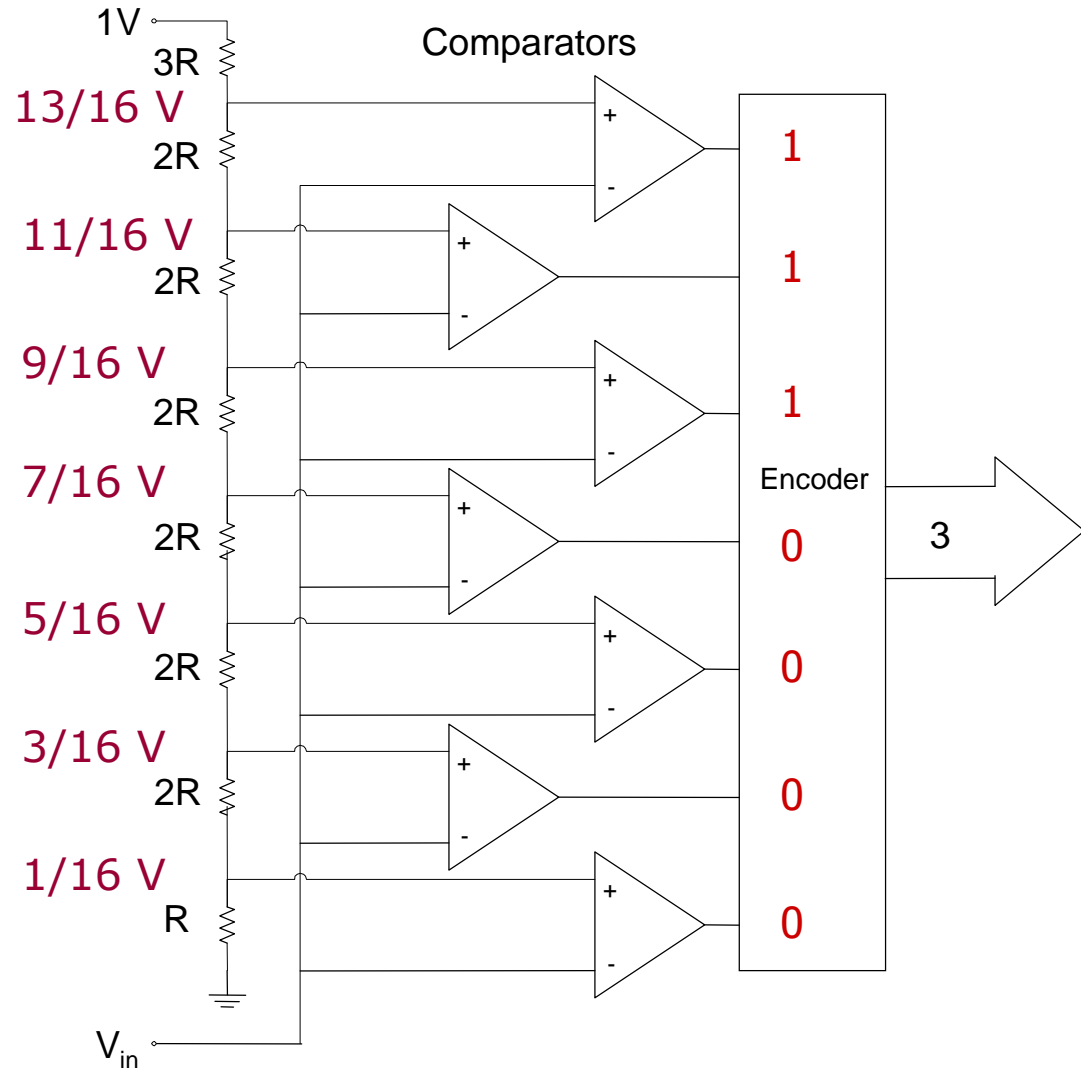
A/D – Flash Conversion

- A multi-level voltage divider
- A comparator is used at each level
- The series of comparator outputs are encoded to a binary number in a priority encoder
- **Components used**
 - 2^N resistors
 - $2^N - 1$ comparators
- **Note**
 - This particular resistor divider generates voltages which are *not* offset by $\frac{1}{2}$ bit, so maximum error is 1 bit



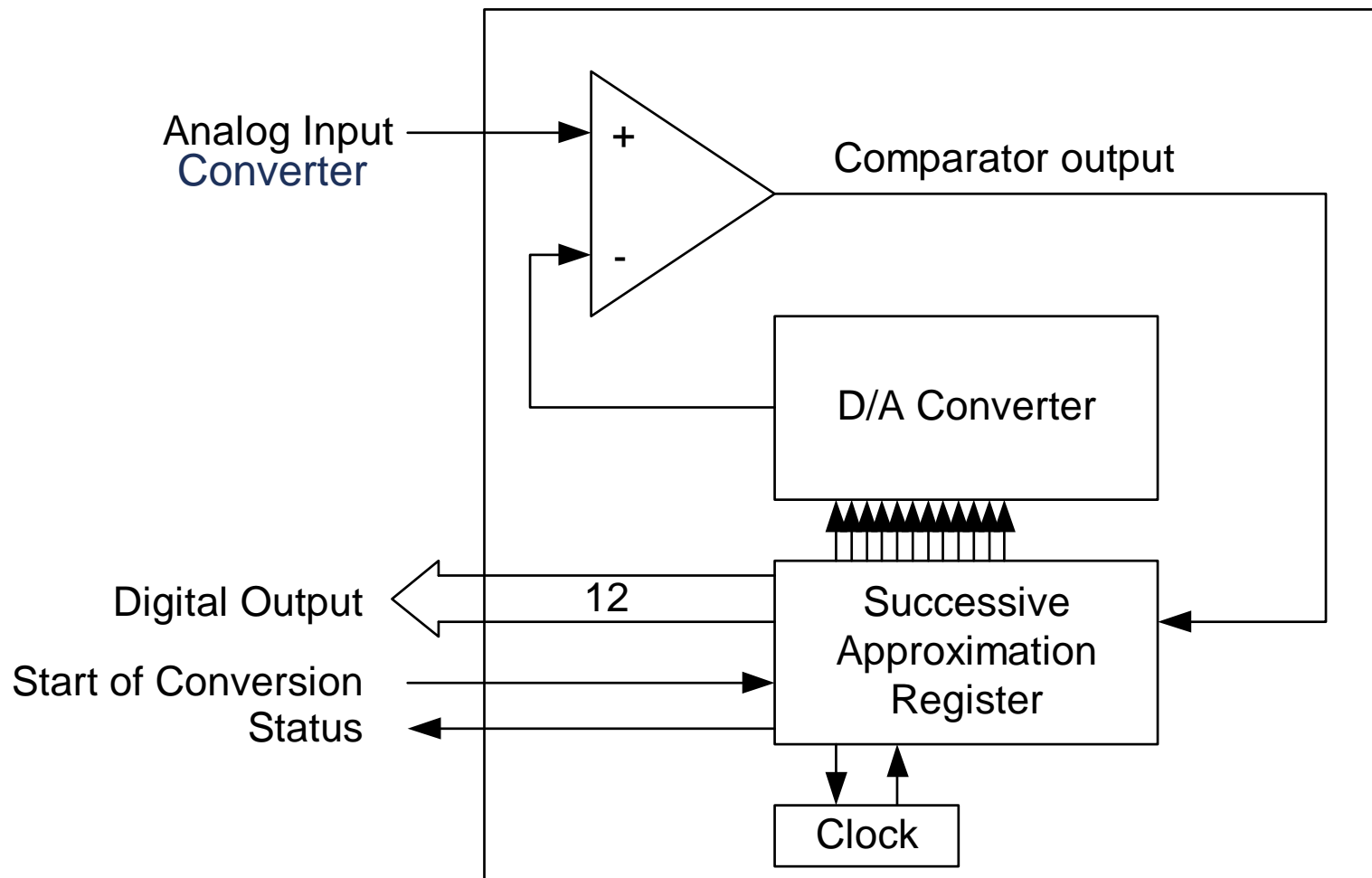
A/D – Flash Conversion

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 - 2^N resistors
 - $2^N - 1$ comparators
- Note
 - This particular resistor divider generates voltages which are *not* offset by $\frac{1}{2}$ bit, so maximum error is 1 bit
 - We could change this offset voltage by using resistors of values $R, 2R, 2R \dots 2R, 3R$ (starting at bottom)



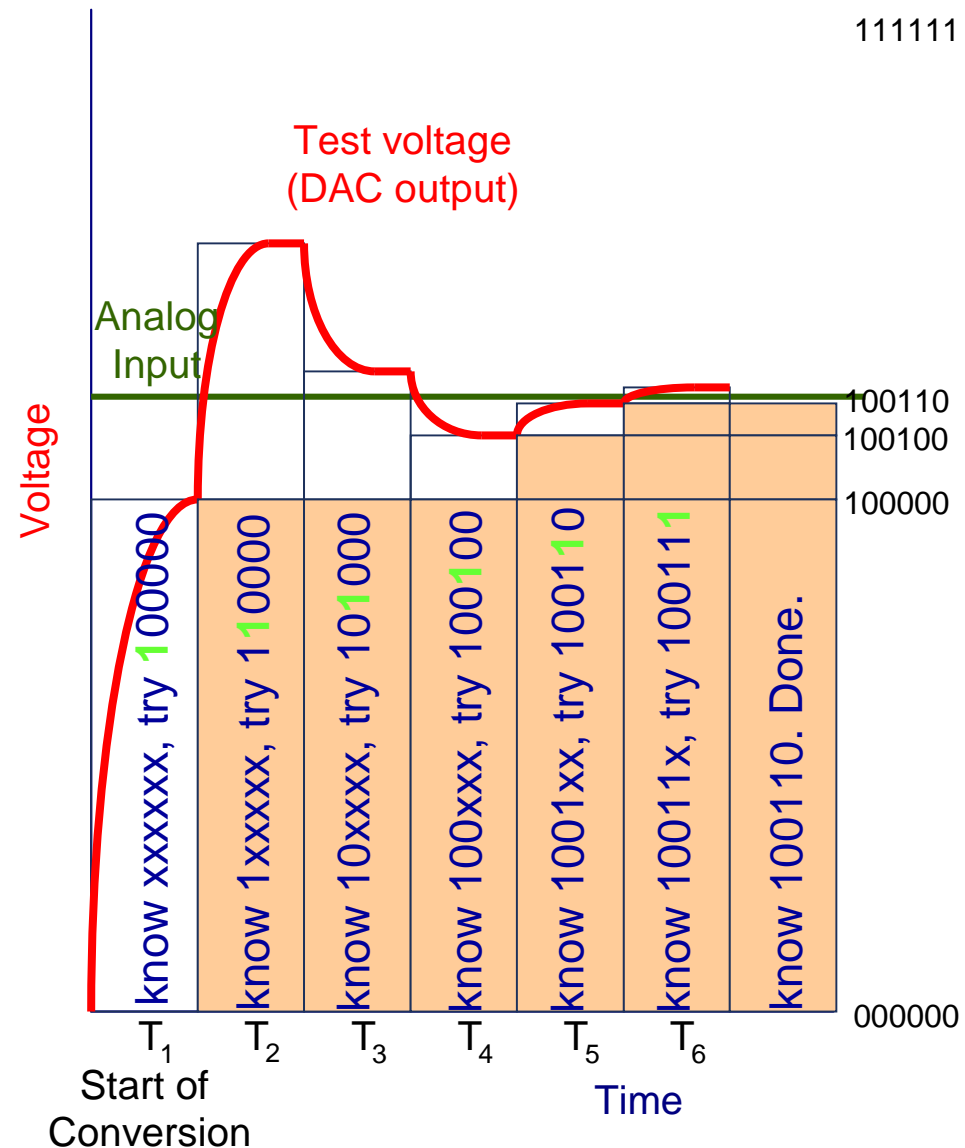
A/D - Successive Approximation

Converter Schematic



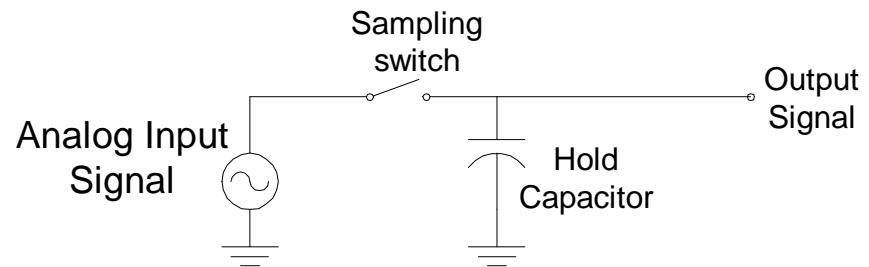
ADC - Successive Approximation Conversion

- Successively approximate input voltage by using a **binary search** and a DAC
- SA Register holds current approximation of result
- Set all DAC input bits to 0
- Start with DAC's most significant bit
- Repeat
 - Set next input bit for DAC to 1
 - Wait for DAC and comparator to stabilize
 - If the DAC output (test voltage) is **smaller** than the input then set the current bit to 1, else clear the current bit to 0



Sample and Hold Devices

- AD conversion takes time (e.g. successive approximation devices)
- So A/D converters require the input analog signal to be held stable during conversion,
- In other cases, peak capture or sampling at a specific point in time necessitates a **sampling device**.
- This function is accomplished by a sample and hold (S&H) device as shown to the right:
- These devices are incorporated into some A/D converters



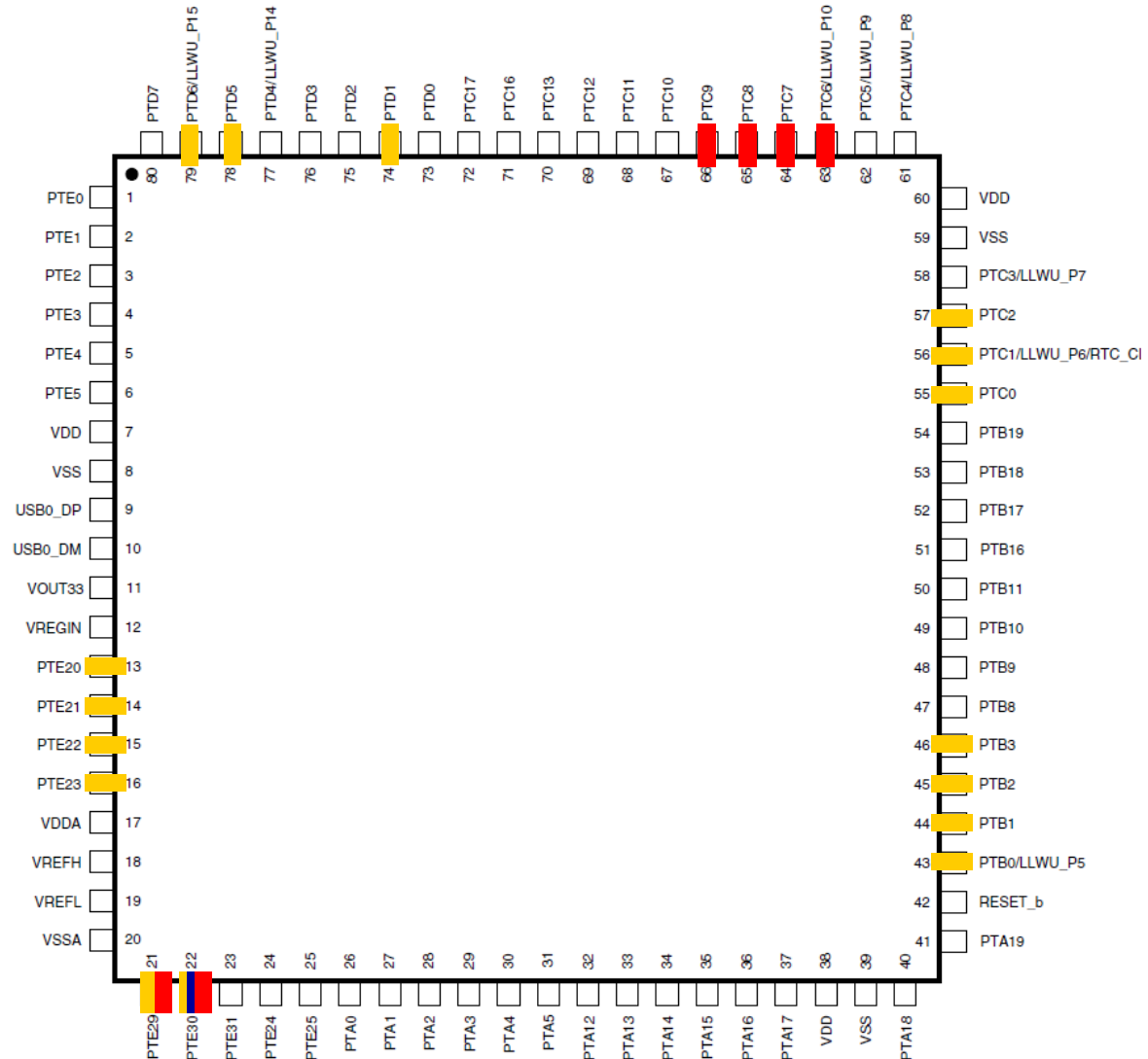
KL25 ANALOG INTERFACING PERIPHERALS

Sources of Information

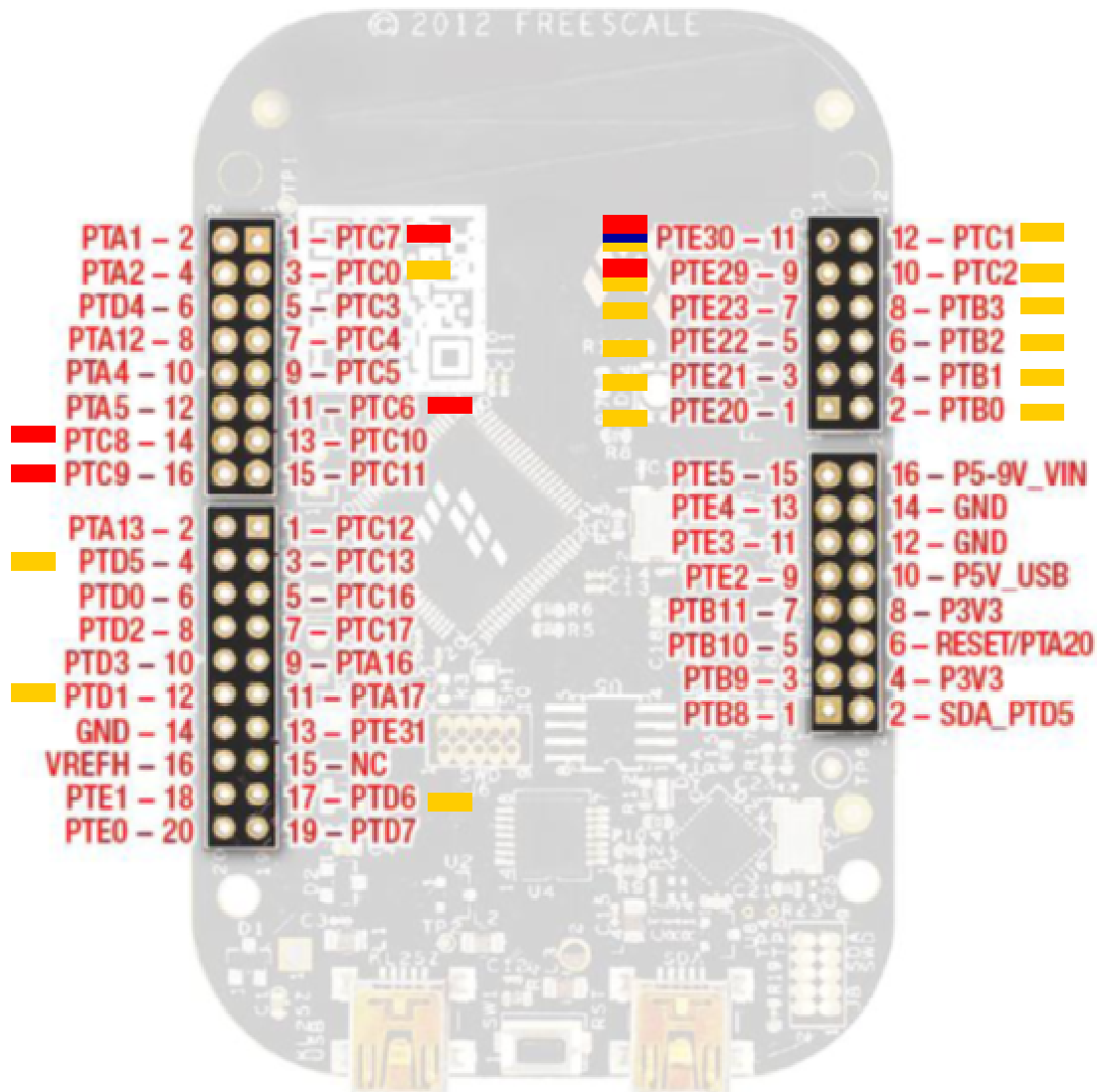
- **KL25 Subfamily Reference Manual (Rev. 1, June 2012)**
 - Describes architecture of peripherals and their control registers
 - Digital to Analog Converter
 - Chapter 30 of KL25 Subfamily Reference Manual
 - Analog Comparator
 - Chapter 29 of KL25 Subfamily Reference Manual
 - Analog to Digital Converter
 - Chapter 28 of KL25 Subfamily Reference Manual
- **KL25 Sub-family Data Sheet (Rev. 3, 9/19/2012)**
 - Describes circuit-specific performance parameters: operating voltages, min/max speeds, cycle times, delays, power and energy use
- **Kinetis L Peripheral Module Quick Reference, Freescale Semiconductor**
 - Gives the valuable examples of programme codes

KL25Z Analog Interface Pins

- 80-pin QFP
- Inputs
 - One 16-bit ADC with 14 input channels
 - One comparator with 6 external inputs and one 6-bit DAC
- Output
 - One 12-bit DAC



Freedom KL25Z Analog I/O



Inputs

14 external ADC channels

6 external comparator channels

Output

1 12-bit DAC

GPIO Port Bit Circuitry in MCU

■ Configuration

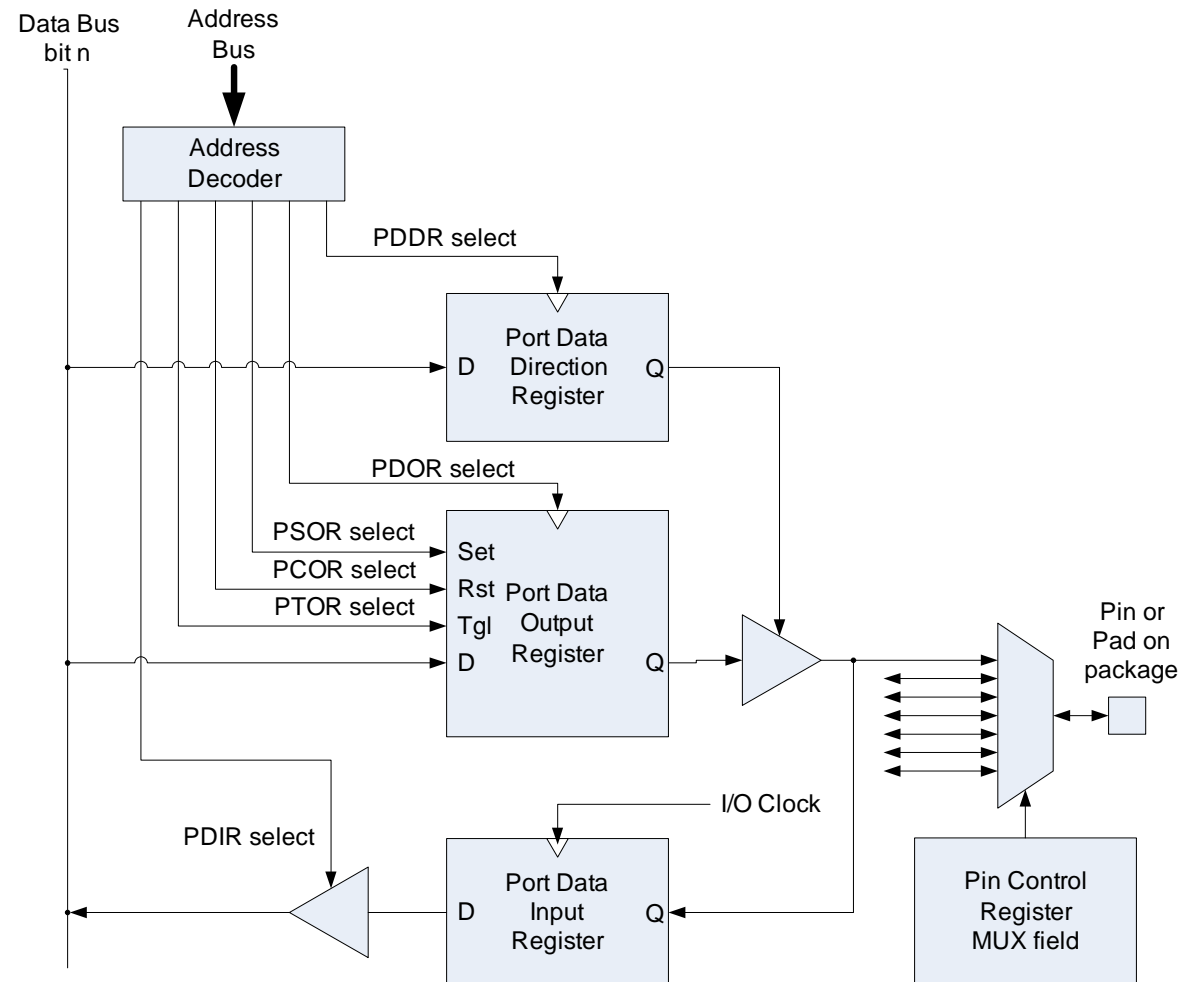
- Direction

- **MUX**

■ Data

- Output (different ways to access it)

- Input



Pin Control Register to Select MUX Channel

Bit	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
R	0					MUX			0	DSE	0	PFE	0	SRE	PE	PS
W																
Reset	0	0	0	0	0	x*	x*	x*	0	x*	0	x*	0	x*	x*	x*

80 LQFP	64 LQFP	48 QFN	32 QFN	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7
64	52	40	28	PTC7	CMP0_IN1	CMP0_IN1	PTC7	SPI0_MISO			SPI0_MOSI		
65	53	—	—	PTC8	CMP0_IN2	CMP0_IN2	PTC8	I2C0_SCL	TPM0_CH4				

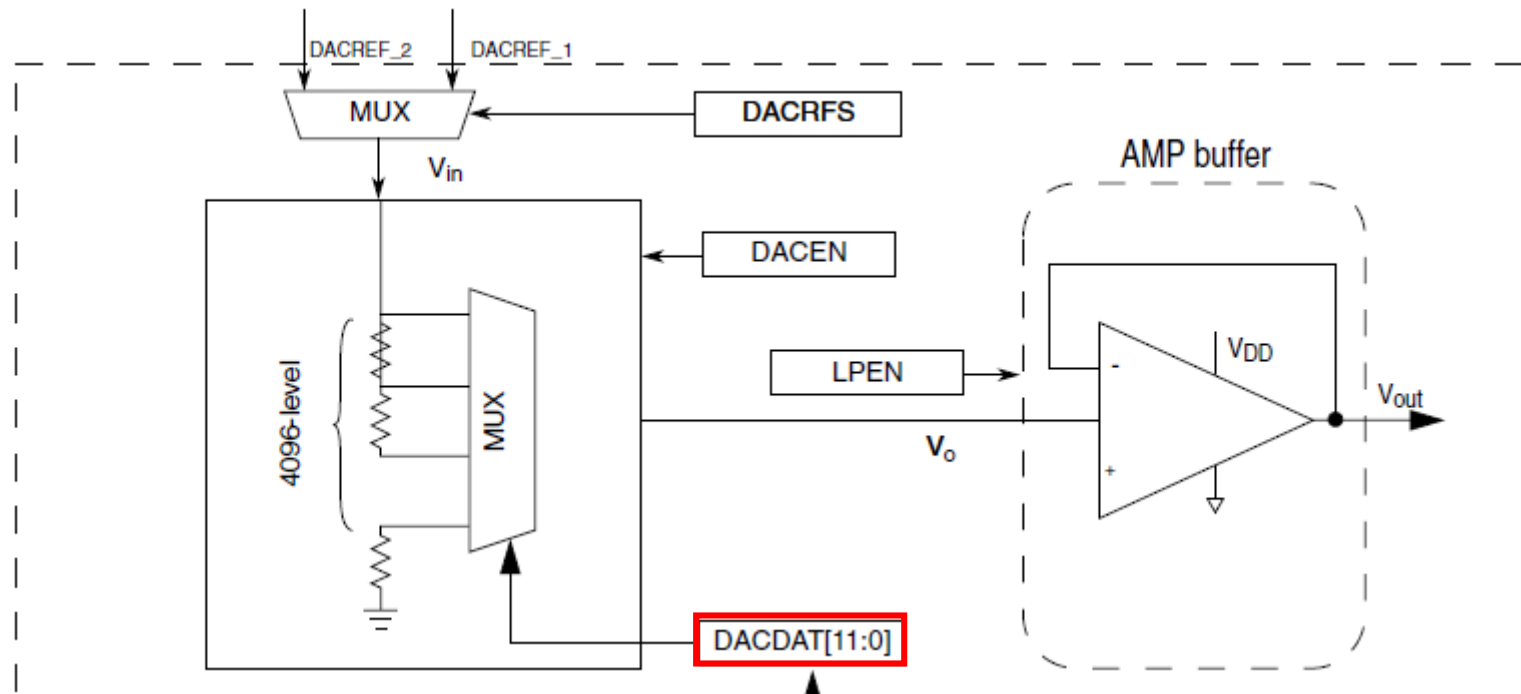
- **MUX field of PCR defines connections**

MUX (bits 10-8)	Configuration
000	Pin disabled (analog)
001	Alternative 1 – GPIO
010	Alternative 2
011	Alternative 3
100	Alternative 4
101	Alternative 5
110	Alternative 6
111	Alternative 7

```
PORTC->PCR[7] &= ~PORT_PCR_MUX_MASK;
PORTC->PCR[7] |= PORT_PCR_MUX(0);
```

DIGITAL TO ANALOG CONVERTER

DAC Overview

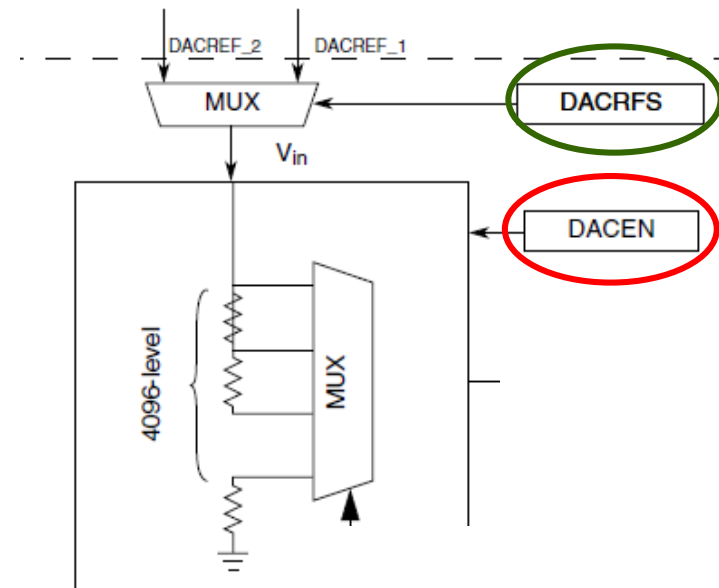


- Load **DACDAT** with 12-bit data N
- MUX selects a node from resistor divider network to create $V_o = (N+1) * V_{in} / 2^{12}$
- V_o is buffered by output amplifier to create V_{out}
 - V_o = V_{out} but V_o is high impedance - can't drive much of a load, so need to buffer it

DAC Control Register 0: DACx_C0

Bit	7	6	5	4	3	2	1	0
Read	DACEN	DACRFS	DACTRGSEL	0	LPEN	0	DACBTEN	DACBBIEN
Write			L	DACSWTRG				
Reset	0	0	0	0	0	0	0	0

- **DACEN** - DAC Enabled when 1
- **DACRFS** - DAC reference voltage select
 - 0: DACREF_1. Connected to VREFH
 - 1: DACREF_2. Connected to VDDA
- **LPEN** - low-power mode
 - 0: High-speed mode. Fast (15 us settling time) but uses more power (up to 900 uA supply current)
 - 1: Low-power mode. Slow (100 us settling time) but more power-efficient (up to 250 uA supply current)
- Additional control registers used for buffered mode



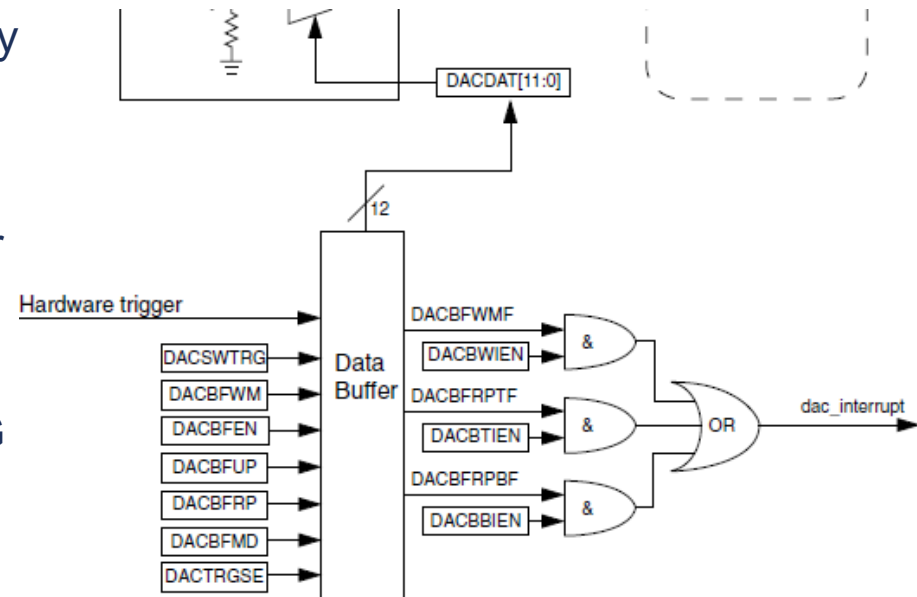
DAC Operating Modes

■ Normal

- DAT0 is converted to voltage immediately

■ Buffered

- Data to output is stored in 16-word buffer
- Next data item is sent to DAC when a selectable trigger event occurs
 - Software Trigger - write to DACSWTRG field in DACx_C0
 - Hardware Trigger - from PIT timer peripheral



- **DACBFEN** - DAC Buffer enable
- **DACSWTRG** - DAC Software Trigger
- **DACTRGSE** - DAC Trigger Select (hw/sw)

DAC Data Registers

- DAC registers are only eight bits long
- DATA[11:0] stored in two registers
 - DATA0: Low byte [7:0] in DACx_DATnL
 - DATA1: High nibble [11:0] in DACx_DATnH
 - Nibble is a half of byte

Example: Waveform Generator

Pseudo algorithm:

- **Supply clock to DAC0 module**
 - Set bit 31 of SIM SCGC6 register
- **Set Pin Mux to Analog (0)**
- **Enable DAC**
- **Configure DAC**
 - Reference voltage
 - Low power mode if necessary
 - Normal mode (not buffered)
- **Write to DAC data register**

Init DAC. Example Code

```
void Init_DAC(void) {  
  
    /* Init DAC output */  
    SIM->SCGC6 |= (1UL << SIM_SCGC6_DAC0_SHIFT);  
    SIM->SCGC5 |= (1UL << SIM_SCGC5_PORTE_SHIFT);  
  
    /* Select analog */  
    PORTE->PCR[DAC_POS] &= ~(PORT_PCR_MUX(7))  
  
    /* Disable buffer mode */  
    DAC0->C1 = 0;  
    DAC0->C2 = 0;  
  
    /* Enable DAC, select VDDA as reference voltage */  
    DAC0->C0 = (1 << DAC_C0_DACEN_SHIFT) |  
               (1 << DAC_C0_DACRFS_SHIFT);  
  
}
```

Sinus Waveform Generator Example

```
extern unsigned sineTable[]; /* sinus values look-up table */

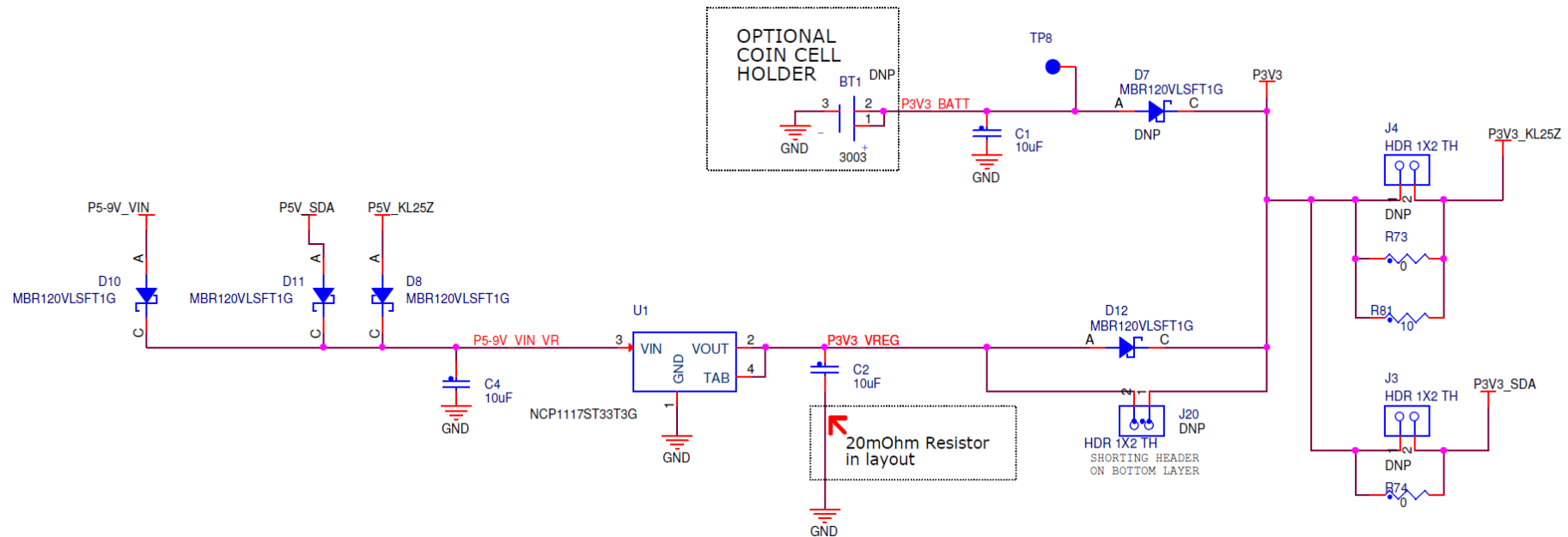
void sinGen(unsigned int period, unsigned int num_cycles ) {
    unsigned step, out_data;

    while (num_cycles>0) {
        num_cycles--;
        for (step = 0; step < NUM_STEPS; step++) {
            out_data = sineTable[step];
            /* Put next sin() value in DATA register */
            DAC0->DAT[0].DATH = DAC_DATH_DATA1(out_data >> 8);
            DAC0->DAT[0].DATL = DAC_DATL_DATA0(out_data);

            Delay_us(period/NUM_STEPS);
        }
    }
}
```

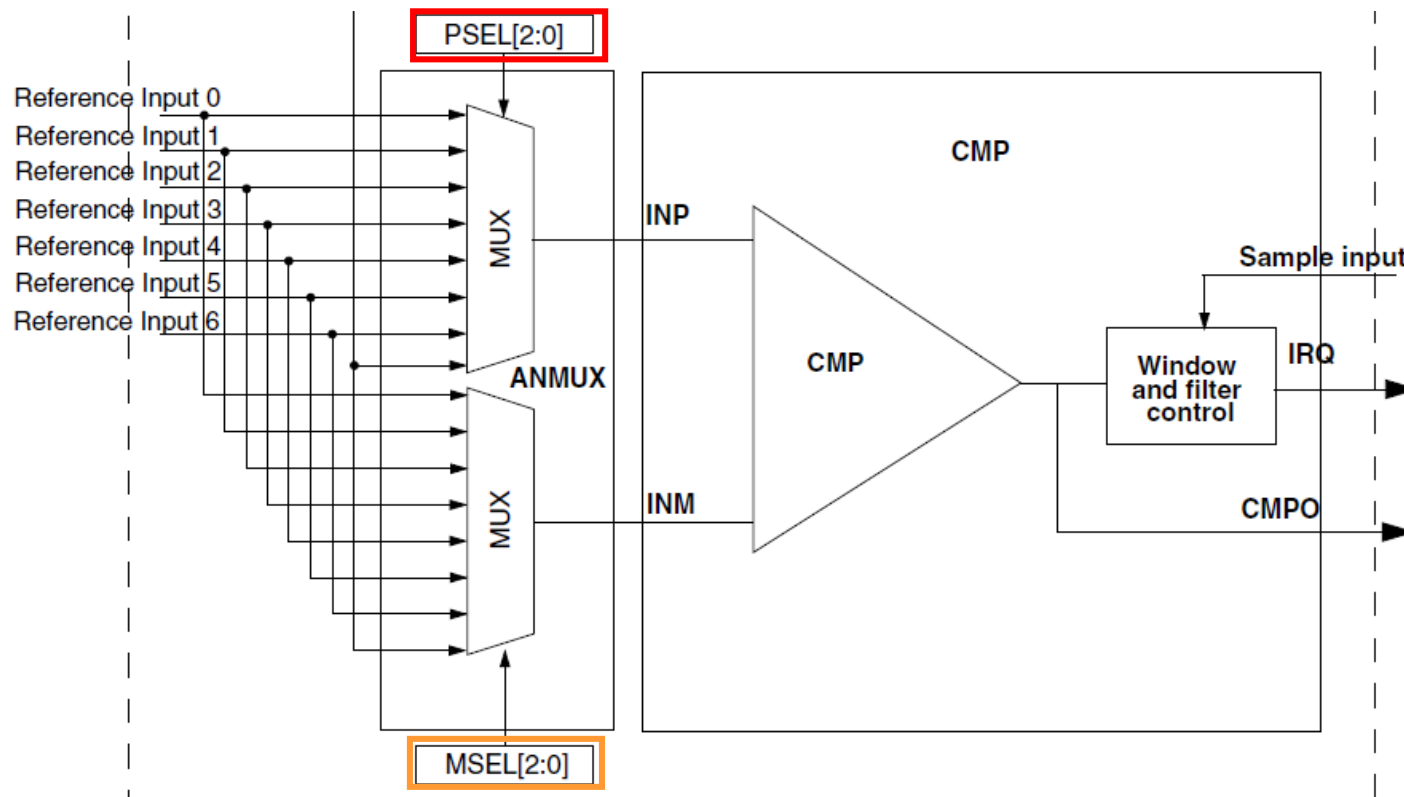
ANALOG COMPARATOR

Example: Power Failure Detection



- Need warning of when power has failed
 - Very limited amount of time before capacitor C2 discharges
 - Save critical information
 - Turn off output devices
 - Put system into safe mode
- Can use a comparator to compare V_{in} against a fixed reference voltage V_{Ref}

Comparator Overview



- Comparator compares INP and INM
- CMPO Output indicates if $INP > INM$ (1) or $INP < INM$ (0)
- Can generate an interrupt request (+, -, or +- edges)
- ANMUX selection of one of multiple reference inputs, using **PSEL** and **MSEL** fields

CMP Control Register 1 CMPx_CR1

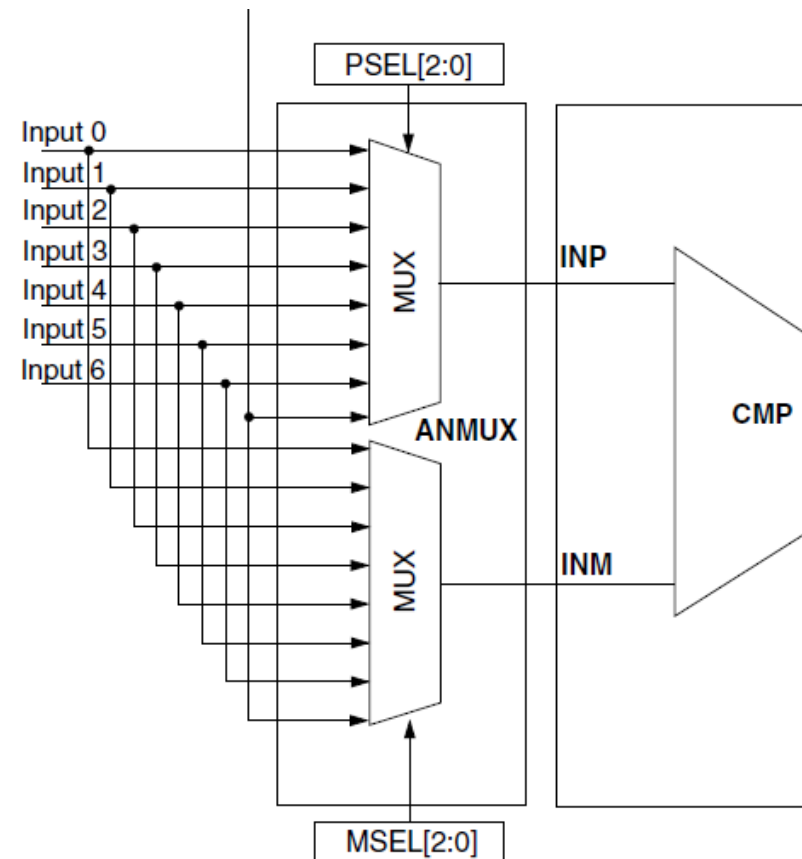
Bit	7	6	5	4	3	2	1	0
Read	SE	WE	TRIGM	PMODE	INV	COS	OPE	EN
Write								
Reset	0	0	0	0	0	0	0	0

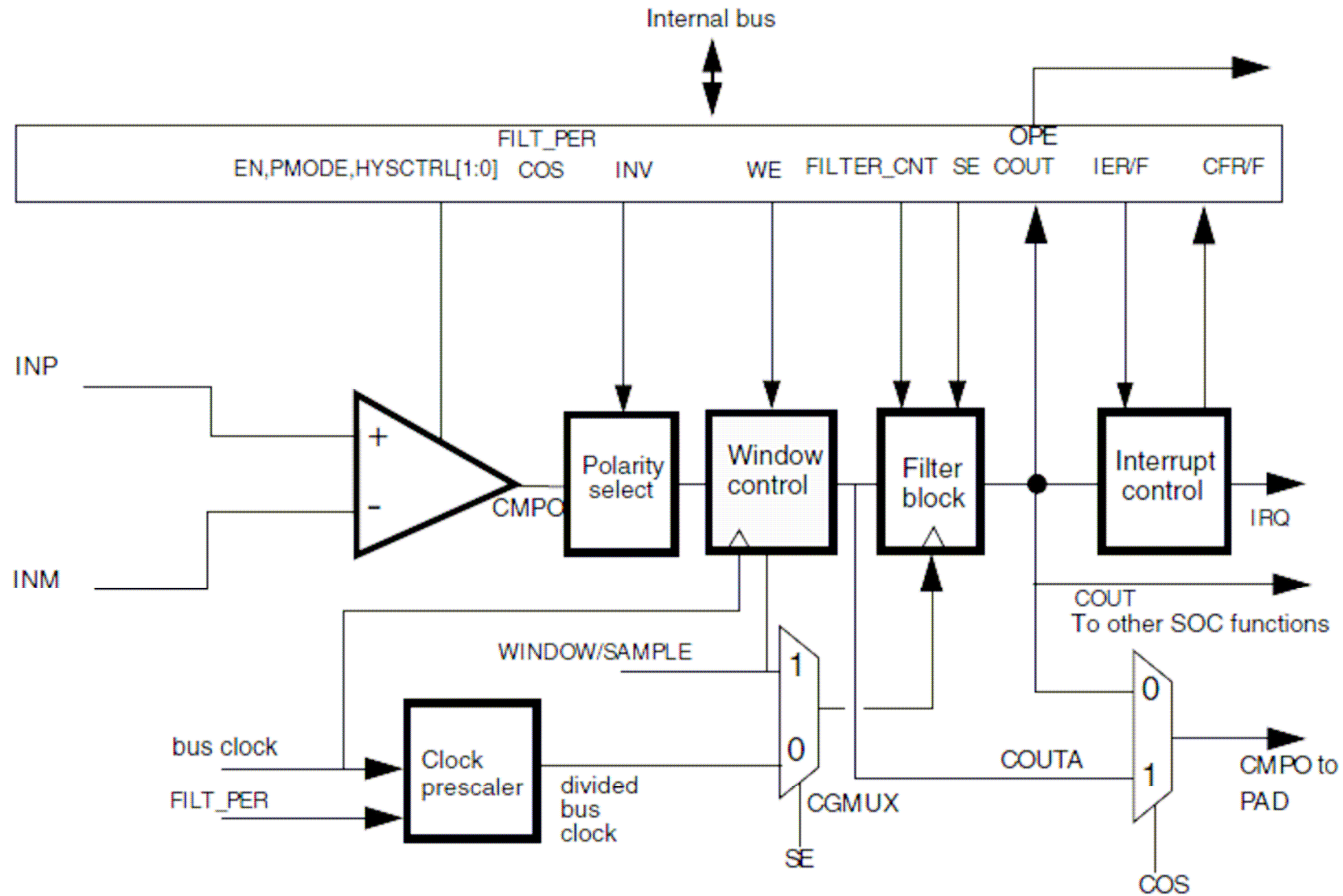
- **EN: Module enable (1)**
- **OPE: Output Pin Enable**
 - 1: connects comparator output signal CMPO to output pin
- **PMODE: Power Mode Select**
 - 0: Low speed
 - 1: High speed

MUX Control Register CMPx_MUXCR

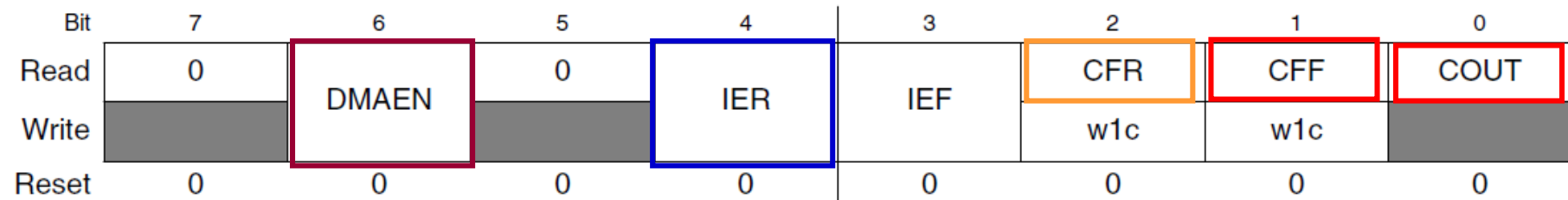
Bit	7	6	5	4	3	2	1	0
Read	0	PSTM	PSEL			MSEL		
Write								
Reset	0	0	0	0	0	0	0	0

- **PSEL: Plus Input Mux Control**
 - Selects which input (IN0-7) goes to the comparator's + input
- **MSEL: Minus Input Mux Control**
 - Selects which input (IN0-7) goes to the comparator's - input



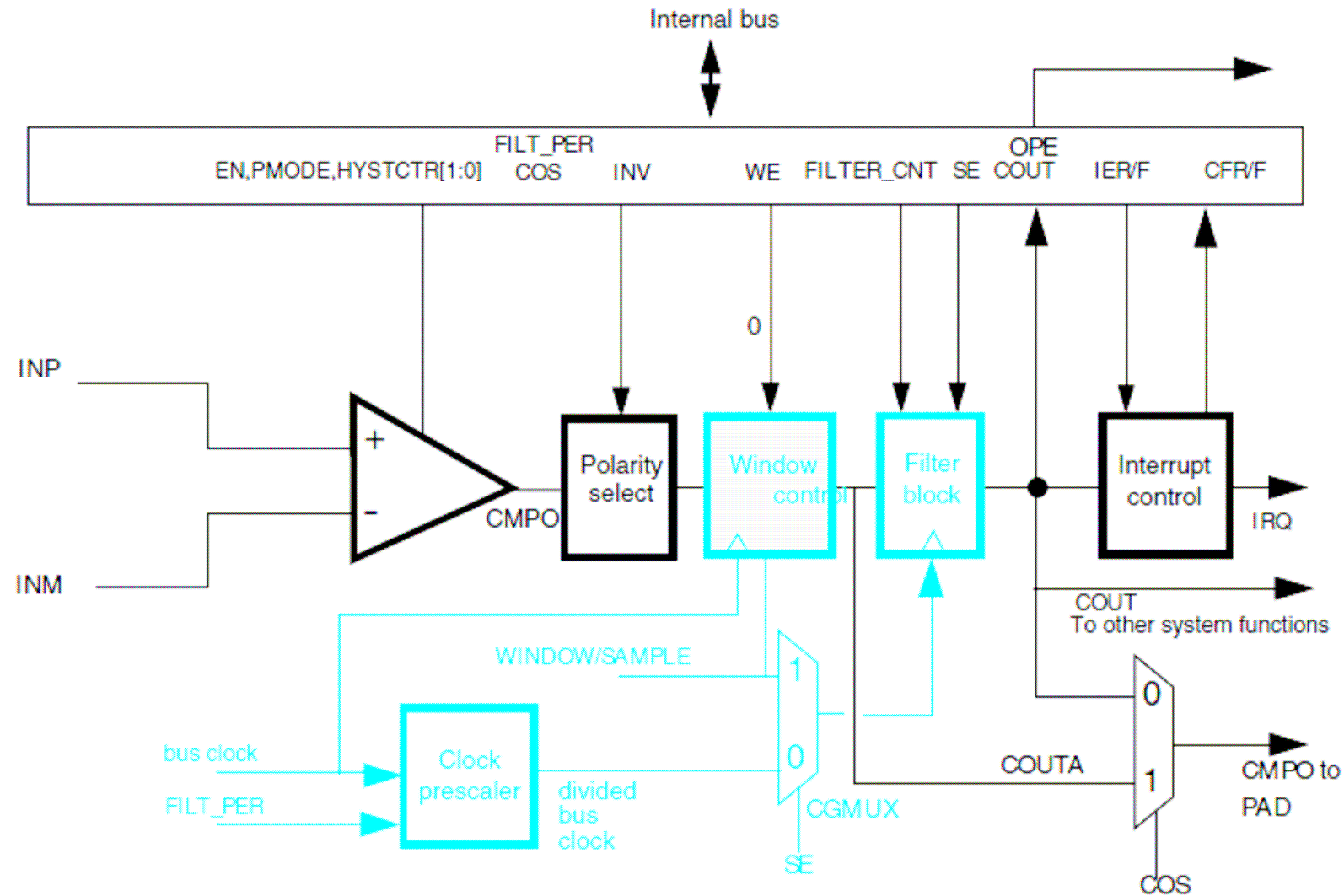


Comparator Interrupt

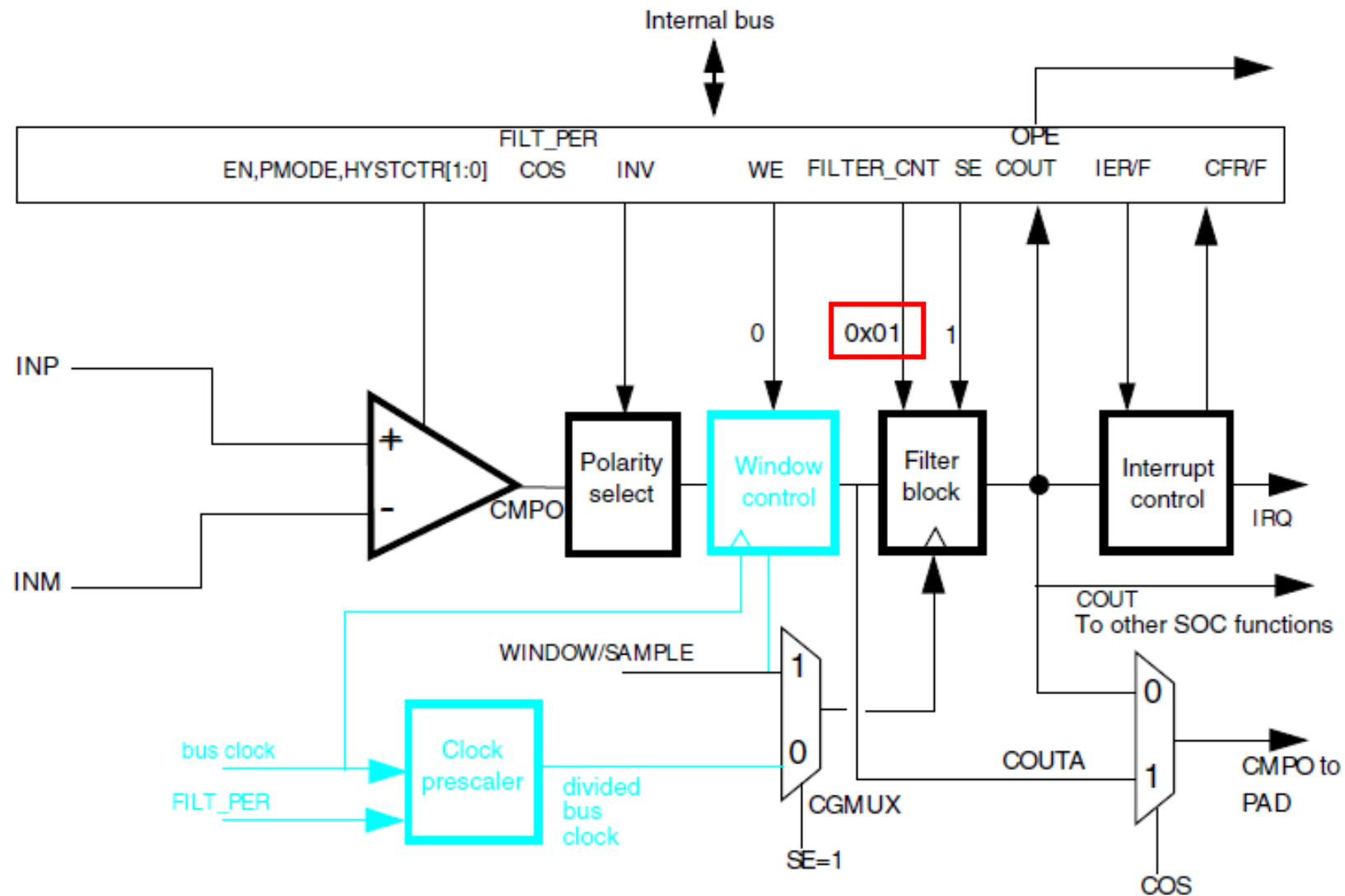


- **CMPx_SCR: Status and control register**
 - **COUT**: output of comparator
 - **CFR**: Comparator flag rising. Rising edge detected on comparator output COUT. Clear flag by writing with a 1.
 - **CFF**: Comparator flag falling. Falling edge detected on comparator output COUT. Clear flag by writing with a 1.
 - **IER**: 1 enables interrupt when CFR is set.
 - **IEF**: 1 enables interrupt when CFF is set.
- **Can generate interrupt on matching edge**
 - CMSIS-defined ISR name for Comparator Interrupt is **CMP0_IRQHandler**

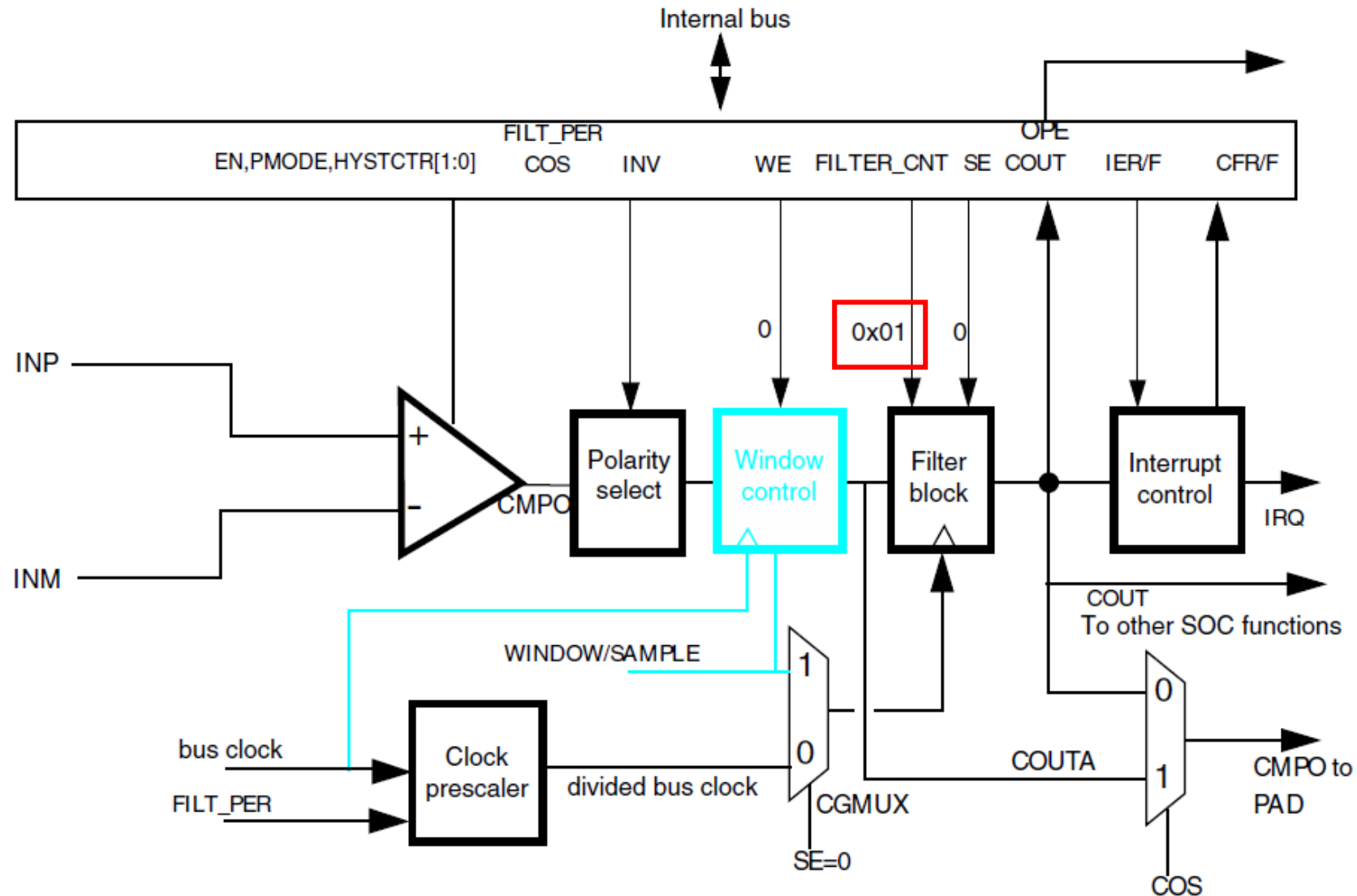
Continuous Mode. SE=0 WE=0 F_CNT=0



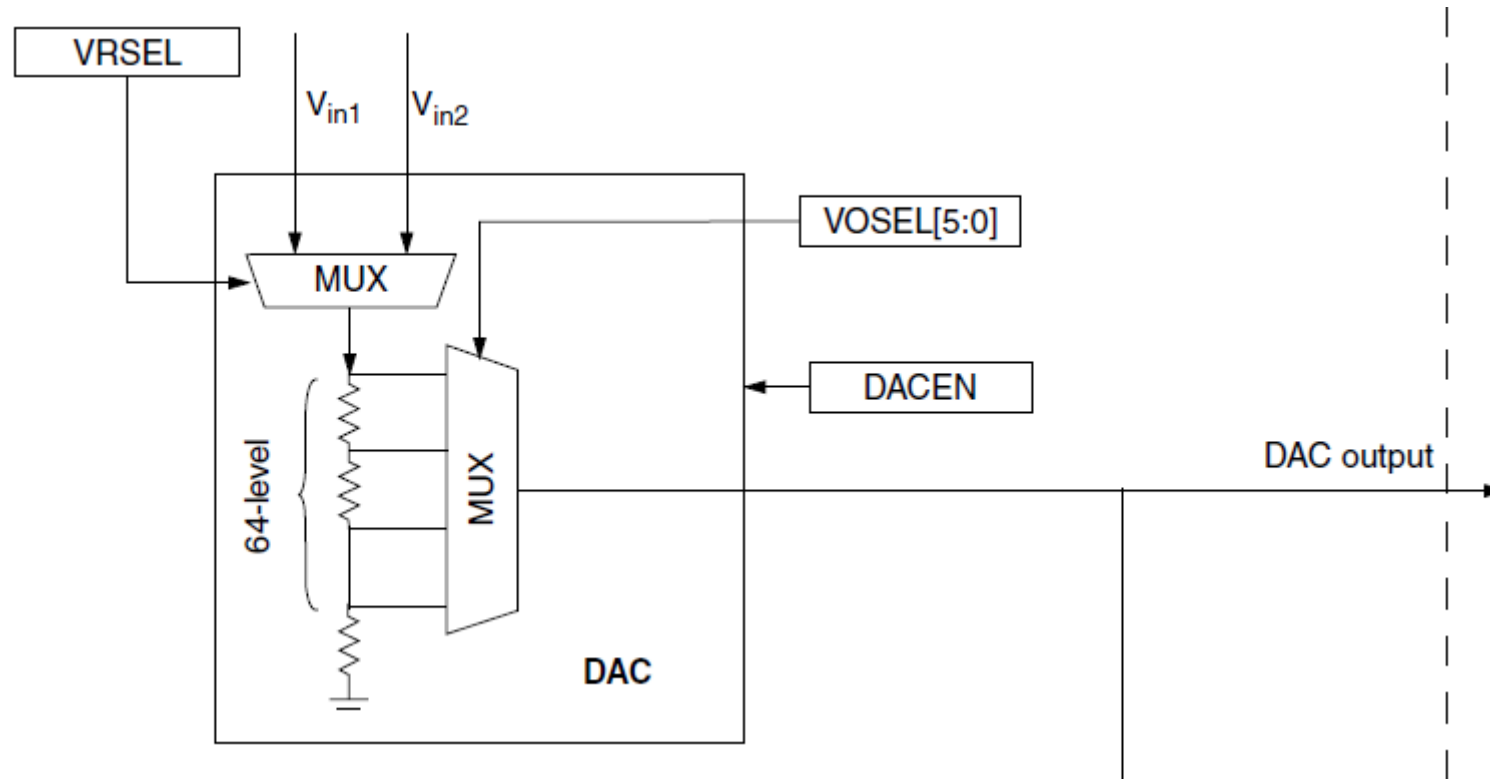
Sampled Mode. SE=1, WE=0, F_CNT>0



Sampled Mode. SE=0, WE=0, F_CNT>0

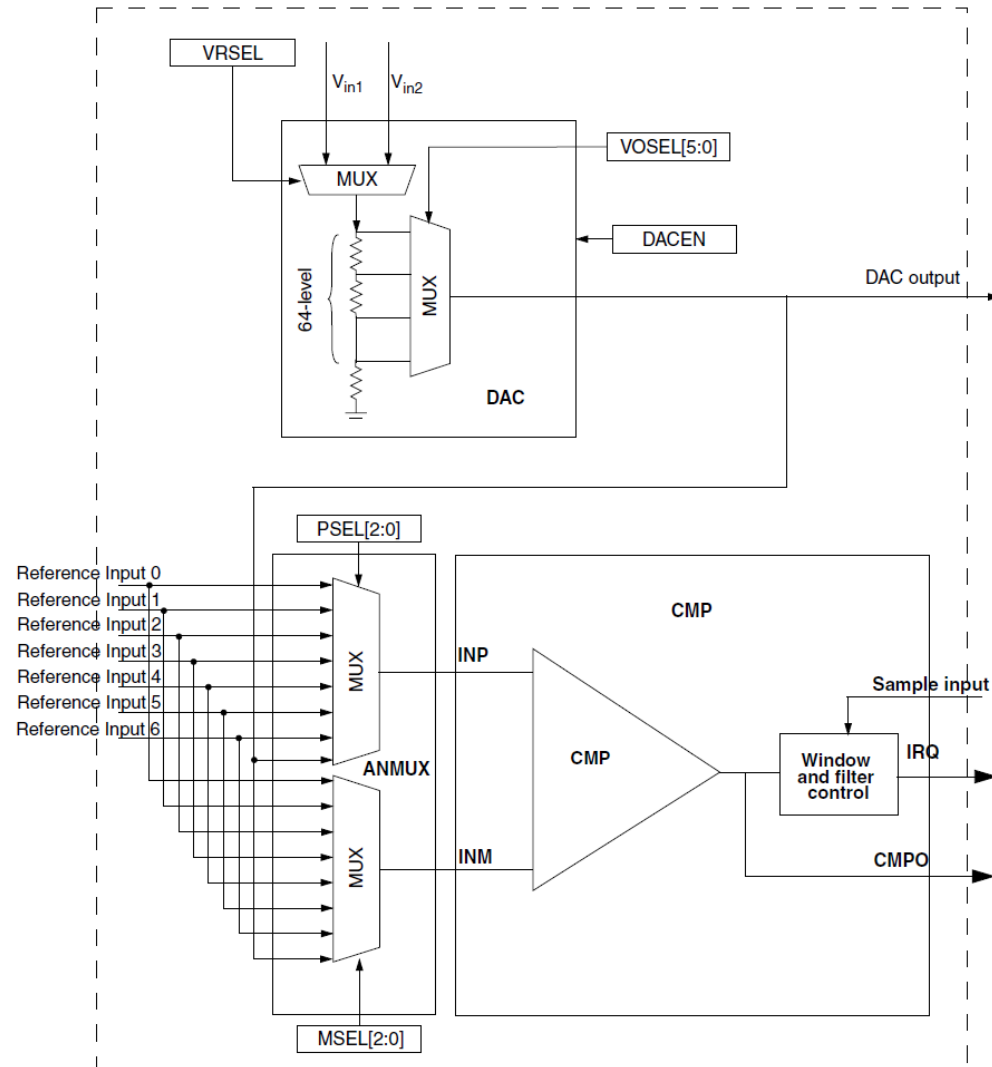


Comparator DAC



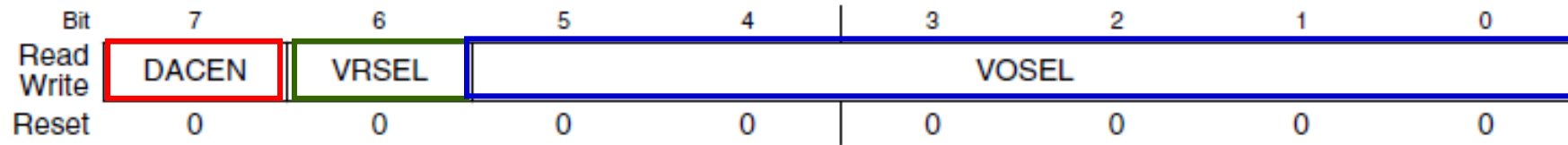
- Can set own reference voltage for comparator
- 6-bit DAC

Programmable Threshold for Comparator

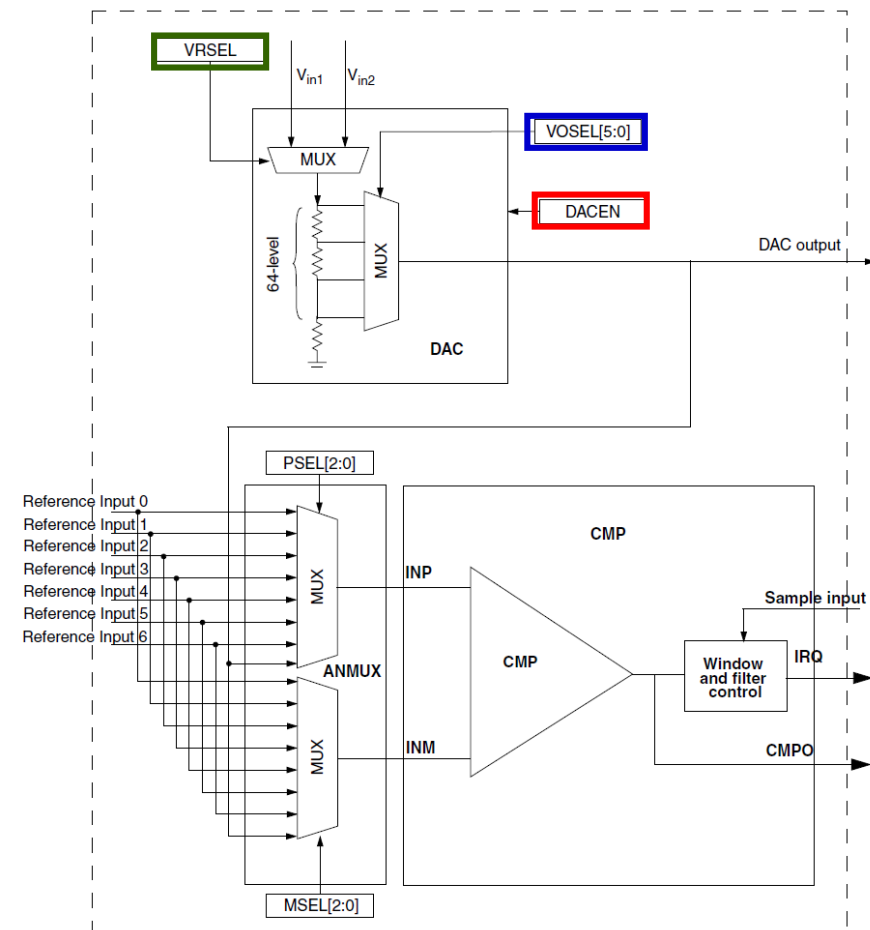


- Can use DAC to set threshold voltage for comparator

DAC Control Register CMPx_DACCR



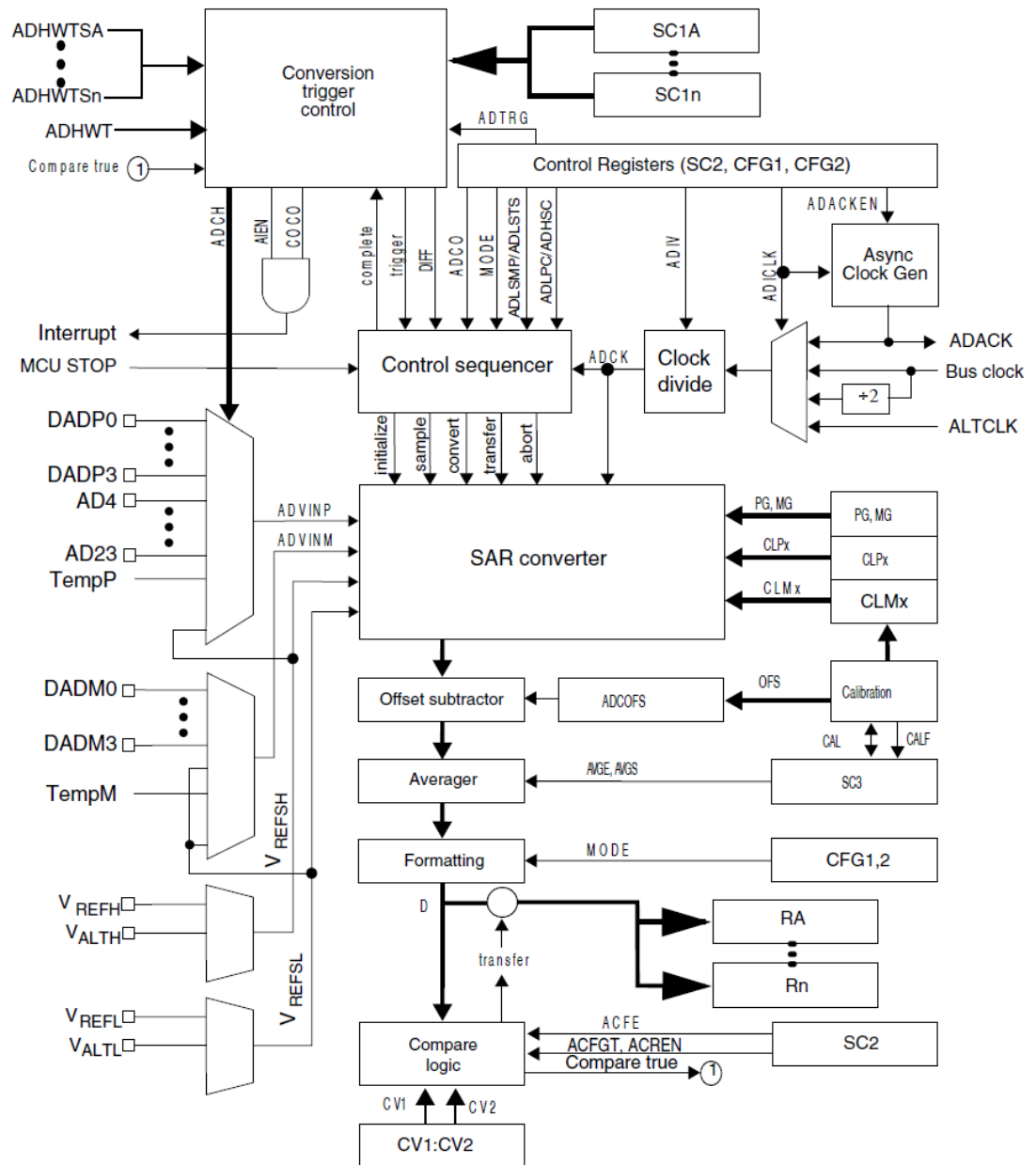
- **DACEN**: Enable CMP DAC (1)
- **VRSEL**: DAC reference voltage select
 - 0: Connected to VREFH
 - 1: Connected to VDD
- **VOSEL**: Output voltage select
 - $V_{DACO} = (VOSEL+1) * (V_{in}/64)$
 - $VOSEL = 64 * (V_{DACO} / V_{in}) - 1$



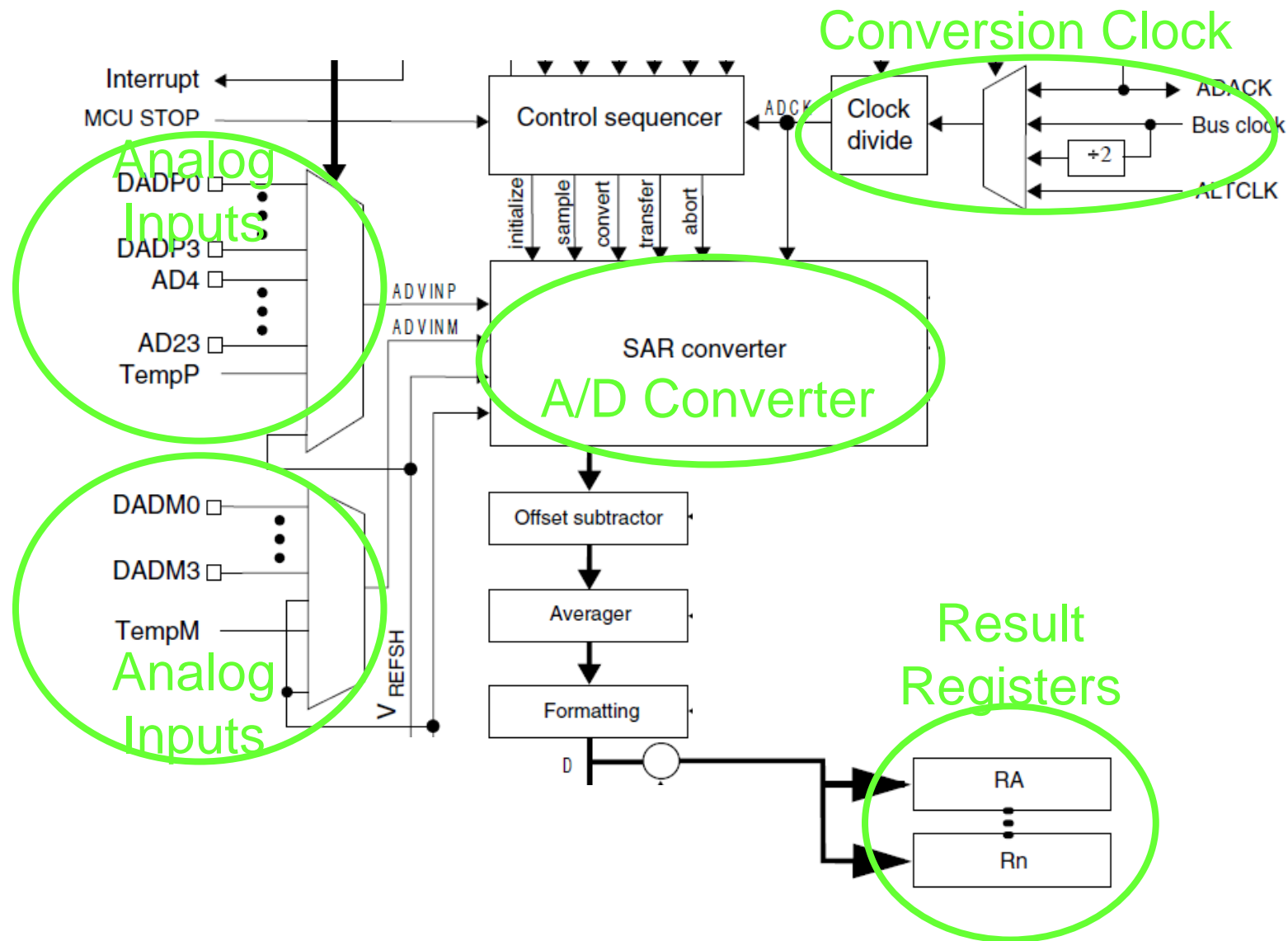
ANALOG TO DIGITAL CONVERTER

ADC Overview

- Uses **SAR** for conversion
- Supports multiple resolutions: 16, 13, 12, 11, 10, 9, and 8 bits
- Up to 24 analog inputs supported (single-ended), 4 pairs of differential inputs
- Signed or unsigned results available
- Automatic compare and interrupt for level and range comparisons
- Hardware data averaging
- Built-in Temperature sensor



ADC System Fundamentals



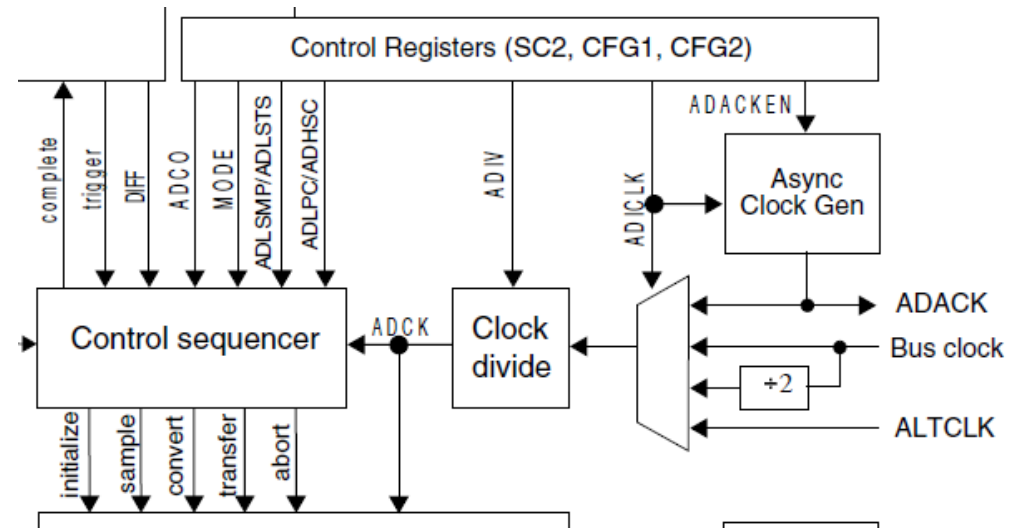
Using the ADC

- **ADC initialization**
 - Configure clock
 - Select voltage reference
 - Select trigger source (hardware or software)
 - Select input channel
- **Trigger conversion**
- **Read results**

Clock Configuration

- Clock sources

- Bus Clock (default)
- ADACK: Local clock, allows ADC operation while rest of CPU is in stop mode
- ALTCLK: alternate clock (MCU-specific)



- Clock divider by a selected factor
- Resulting ADCK must be within valid range to ensure accuracy (See KL25 Subfamily datasheet)
 - 1 to 18 MHz (\leq 13-bit mode)
 - 2 to 12 MHz (16-bit mode)

Clock Configuration Registers

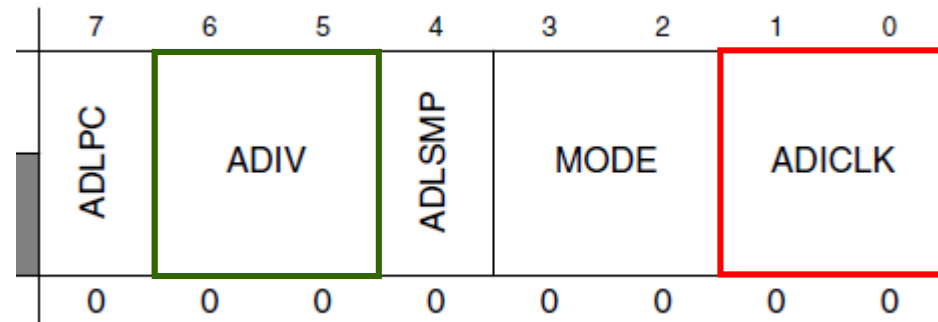
■ ADCx_CFG1

■ **ADICLK**: Input clock select

- 00: Bus clock
- 01: Bus clock/2
- 10: ALTCLK
- 11: ADACK

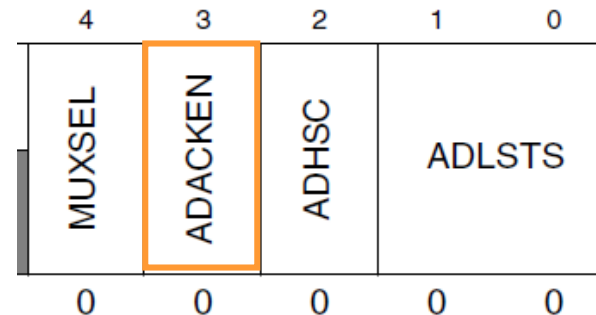
■ **ADIV**: divide clock by 2^{ADIV}

- 00: 1
- 01: 2
- 10: 4
- 11: 8



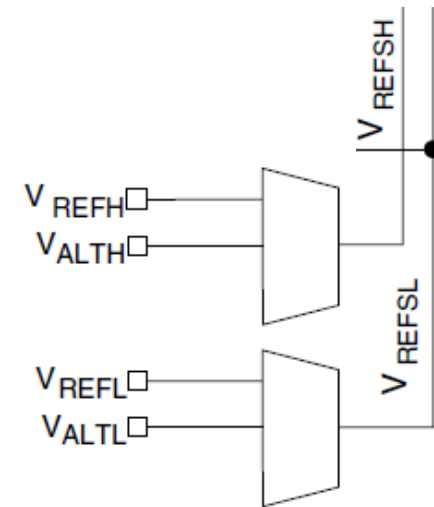
■ ADCx_CFG2

- **ADACKEN**: Enable asynchronous clock



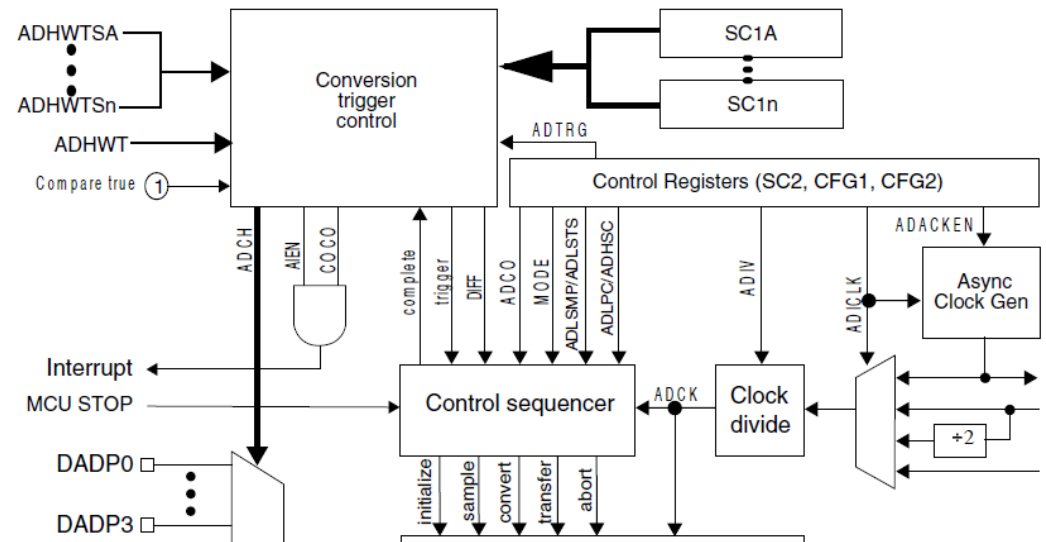
Voltage Reference Selection

- Two voltage reference pairs available
 - V_{REFH} , V_{REFL}
 - V_{ALTH} , V_{ALTL}
- Select with SC2 register's REFSEL bits
 - 00: V_{REFH} , V_{REFL}
 - 01: V_{ALTH} , V_{ALTL}
 - 10, 11: Reserved
- KL25Z
 - V_{ALTH} connected to V_{DDA}



Conversion Trigger Selection

- **Two SC1 registers:**
 - SC1A and SC1B
- **ADTRG in SC2**
 - 0: software trigger
 - 1: hardware trigger
- **Software trigger:**
 - Programme writes to SC1A
- **Ping-pong buffering**
 - SC1A vs. SC1n
- **Hardware trigger:**
 - Rising edge of ADHWT signal
 - ADHWT sources: TPM, LPTMR, PIT, RTC, EXTRG_IN, HSCMP0
 - Selected in System Integration Module
 - SIM_SOPT7 register
 - See section 12.2.6 of Reference Manual



Input Channel Selection

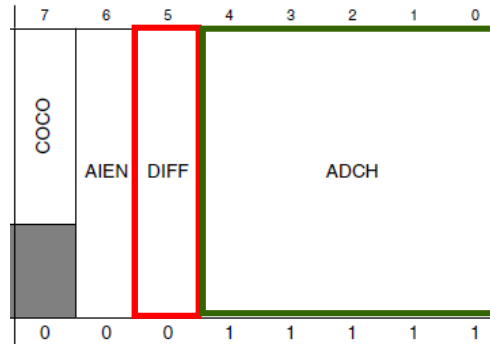
- Two modes, selected by SC1n[DIFF] bit

- 0: Single-ended
- 1: Differential

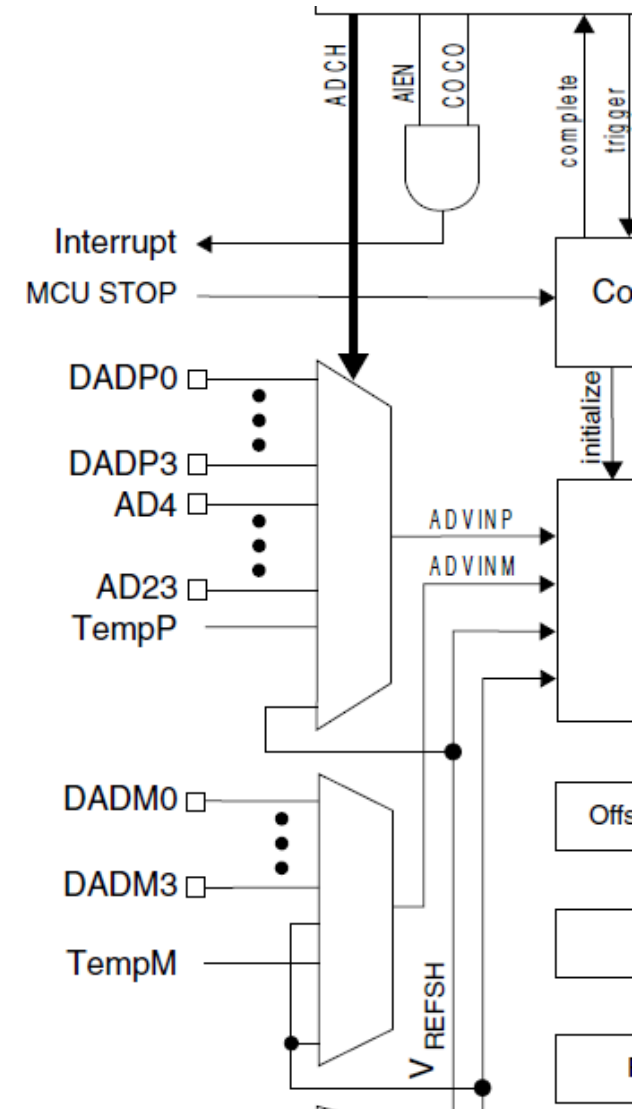
- Input channel selected by value of ADCH

Extras

- Reference voltages
- Temperature
- Band Gap

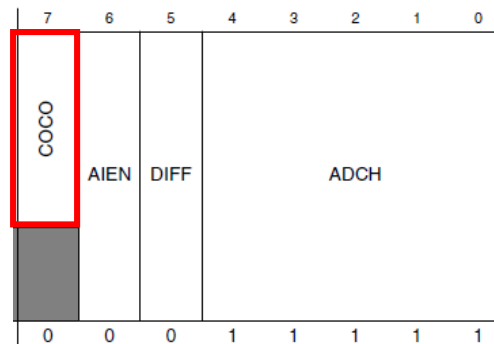


ADCH	DIFF	
	0	1
0	DADP0	DAD0
1	DADP1	DAD1
2	DADP2	DAD2
3	DADP3	DAD3
4	AD4	reserved
...
23	AD23	reserved
24	reserved	reserved
25	reserved	reserved
26	Temp Sensor	
27	Band Gap	
28	reserved	reserved
29	VREFSH	-VREFSH
30	VREFSL	reserved
31	module disabled	



Conversion Completion

- Signaled by **COCO** bit in SC1n
- Can generate conversion complete interrupt if AIEN in SC1 is set
- CMSIS-defined ISR name for ADC Interrupt is **ADC0_IRQHandler**



ADC simple code example

```
/* Initialize ADC */
void Init_ADC(void) {

    SIM->SCGC6 |= (1UL << SIM_SCGC6_ADC0_SHIFT); /* Enable ADC clock */
    ADC0->CFG1 = 0x9C; /* Select 16 bit resolution */
    ADC0->SC2 = 0;
}

/* Perform a voltage single measure */
unsigned Measure (void) {
    volatile unsigned res=0;

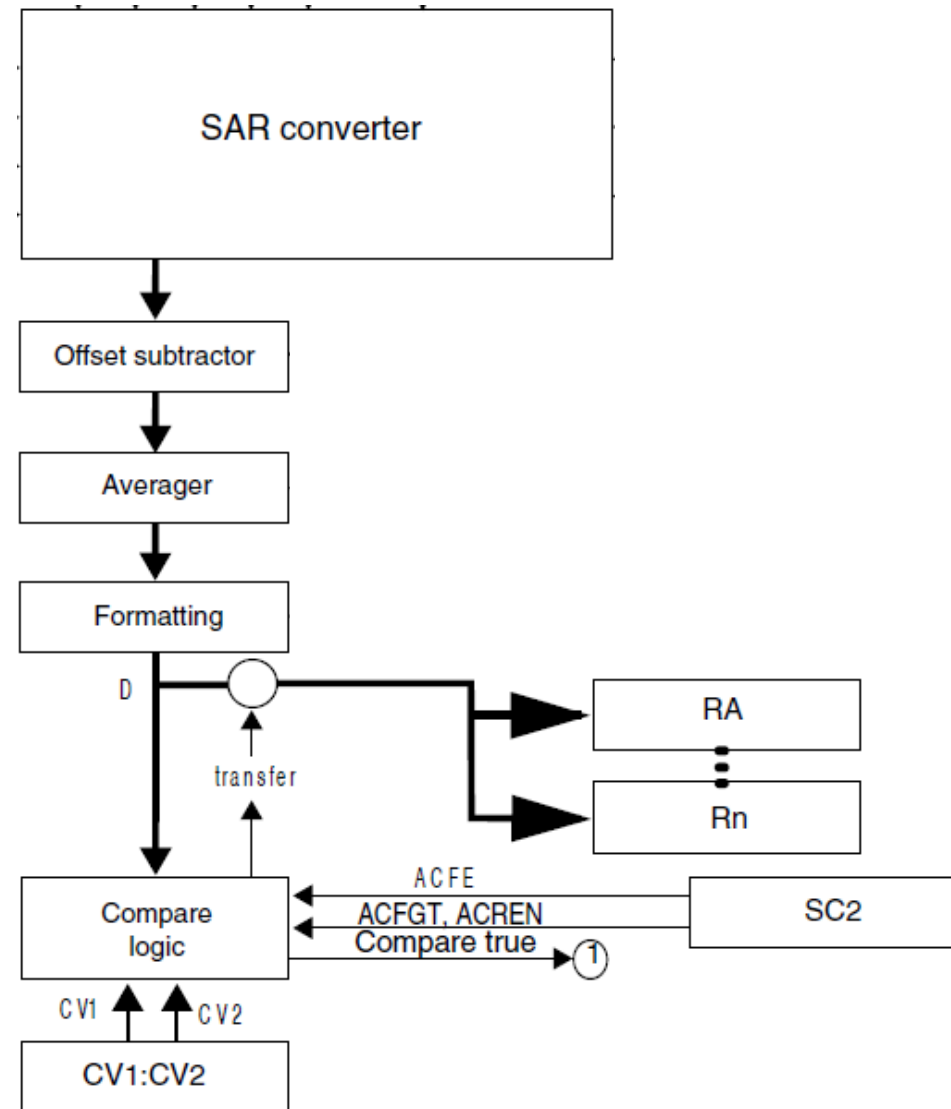
    ADC0->SC1[0] = 0x00; /* start conversion on channel 0 */

    while (!(ADC0->SC1[0] & ADC_SC1_COCO_MASK)) ; /* wait conversion end */
    res = ADC0->R[0]; /* read data from result register */

    return res;
}
```


Result Registers

- **Optional output processing before storage in result registers**
 - Offset subtraction from calibration
 - Averaging: 1, 4, 8, 16 or 32 samples
 - Formatting: Right justification, sign- or zero-extension to 16 bits
 - Output comparison
- **Two result registers RA and RB**
 - Conversion result goes into register corresponding to SC1 register used to start conversion (SC1A, SC1n)



Output Averaging

- Accumulate and average multiple samples before writing the averaged result to the result register
- Result rate = sample rate / averaging factor
- In SC3 register
 - **AVGE**: average enable
 - **AVGS**: average sample count

AVGE	AVGS	Number of samples averaged
0	xx	1
1	00	4
1	01	8
1	10	16
1	11	32

Automatic Compare

- Can ignore ADC result based on comparison with CV1 and CV2
 - Above or equal to threshold
 - Below threshold
 - Outside range
 - Inside range
- Ignored result...
 - **Not saved to RA/Rn**
 - **CoCo not set**

